

# 放射光実験、XAFSとその周辺

-これからXAFSを始める人のために-

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# Outline

- 放射光
- 軟X線領域のXAFS: NEXAFS, XMCD
- 蛍光X線分析 (XRF, XFA)
- (硬X線領域の)XAFS
  - 原子間距離を求める、“長さを測る”、ことについて
  - EXAFSの式、それを得るまでの理論的概念の整理
  - XAFS測定
- Some topics

# 放射光 (Synchrotron Radiation)

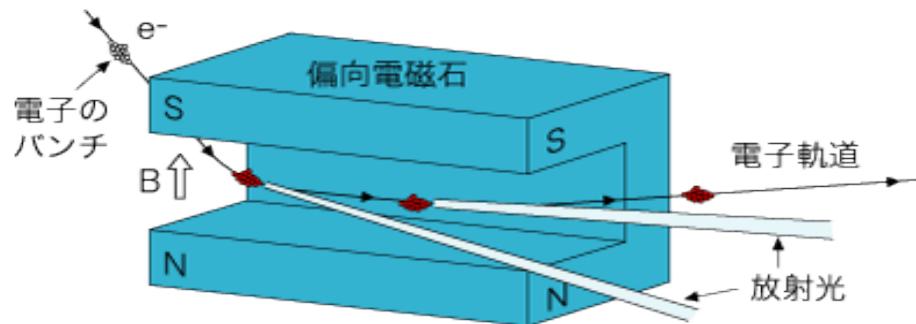
高エネルギーの電子が磁場の中を運動

└ 偏向電磁石 (Bending Magnet), etc.

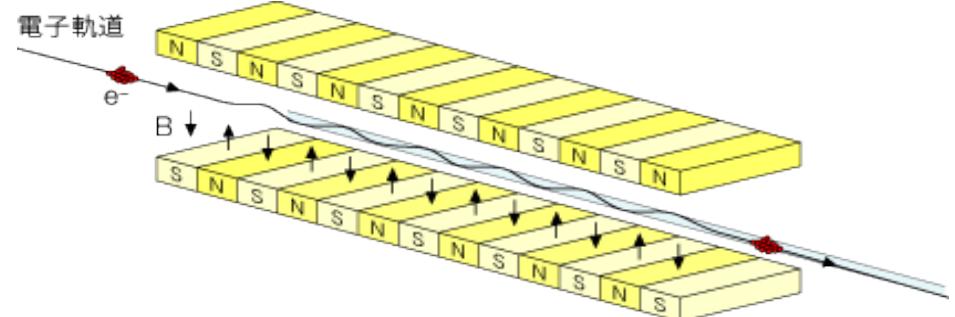
電子: 円運動の中心に向かって力を受け、軌道が曲げられる



電磁波が円軌道の接線方向に放射される; 放射光

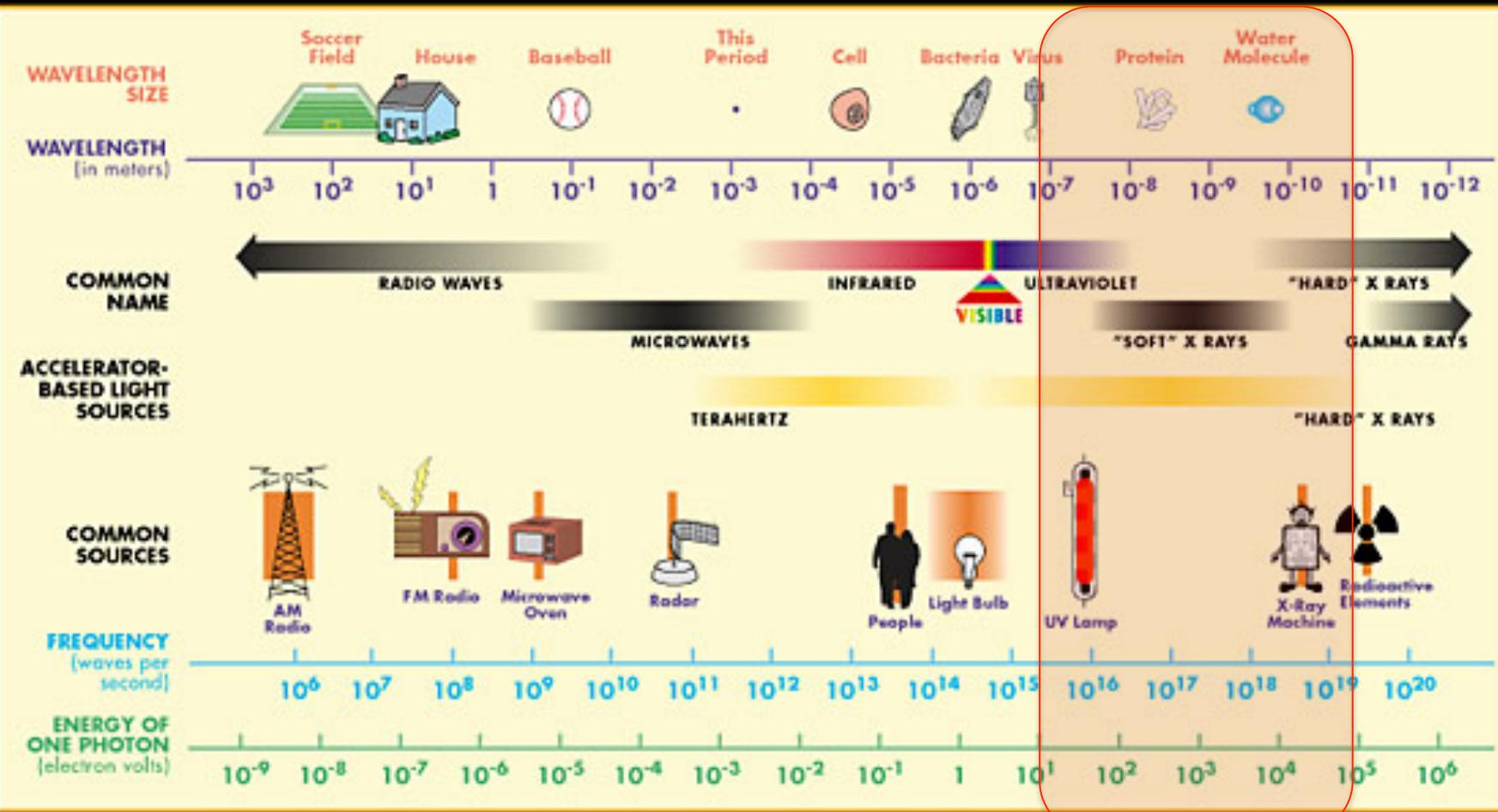


偏向電磁石 (Bending Magnet)

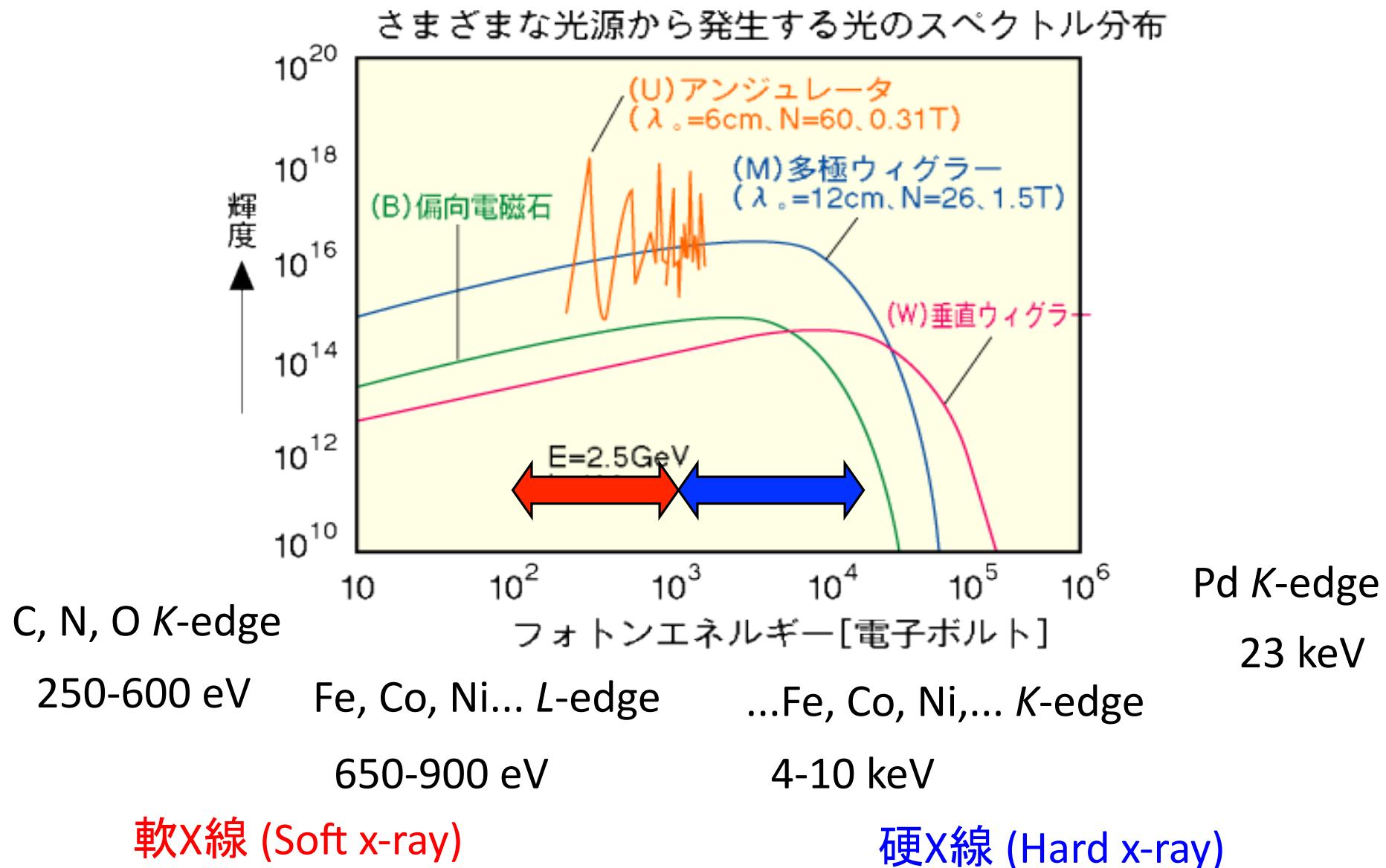


挿入光源 (Insertion Device)  
Undulator, Wiggler

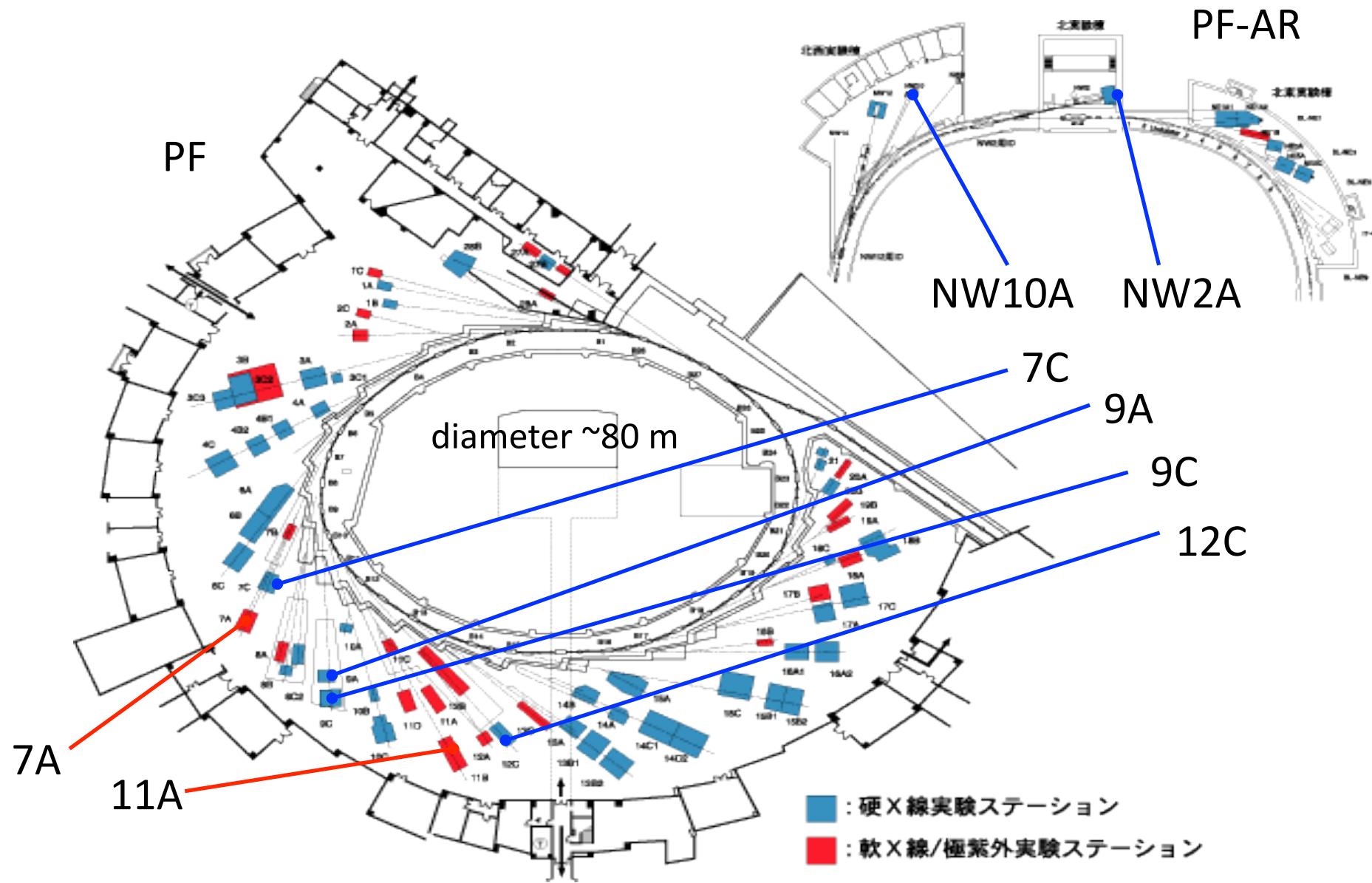
# THE ELECTROMAGNETIC SPECTRUM



# Light sources and spectra



# Beamlines



# XAFS

XAFS: X-ray Absorption Fine Structure, X線吸収微細構造

軟X線領域: ~200 – 2000 eV ← 超高真空が必要  
(Soft x-ray) (~ $10^{-8}$  Pa)

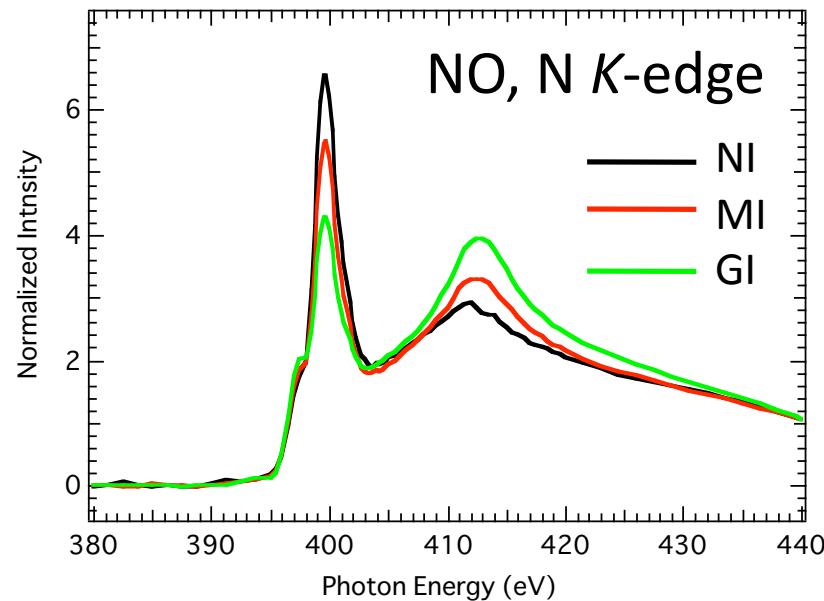
XAS (X-ray Absorption Spectroscopy) とも言う

硬X線領域: ~2 keV – どこまでも  
(Hard x-ray) ~42 keV (at PF-AR NW10A)  
~60 keV, 113 keV (at SPring-8 BL01B1)

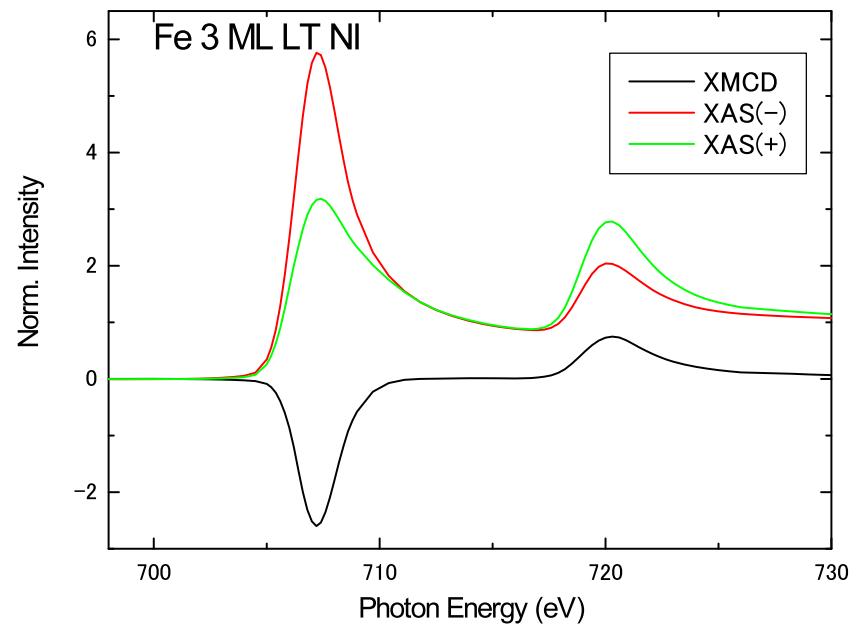
~2 keV – 4 keV: Hard x-rayの中では、"Soft"と呼ばれる

# 軟X線領域のX線吸収分光

NEXAFS: Near Edge X-ray Absorption Fine Structure



XMCD: X-ray Magnetic Circular Dichroism



# NEXAFSから分かること

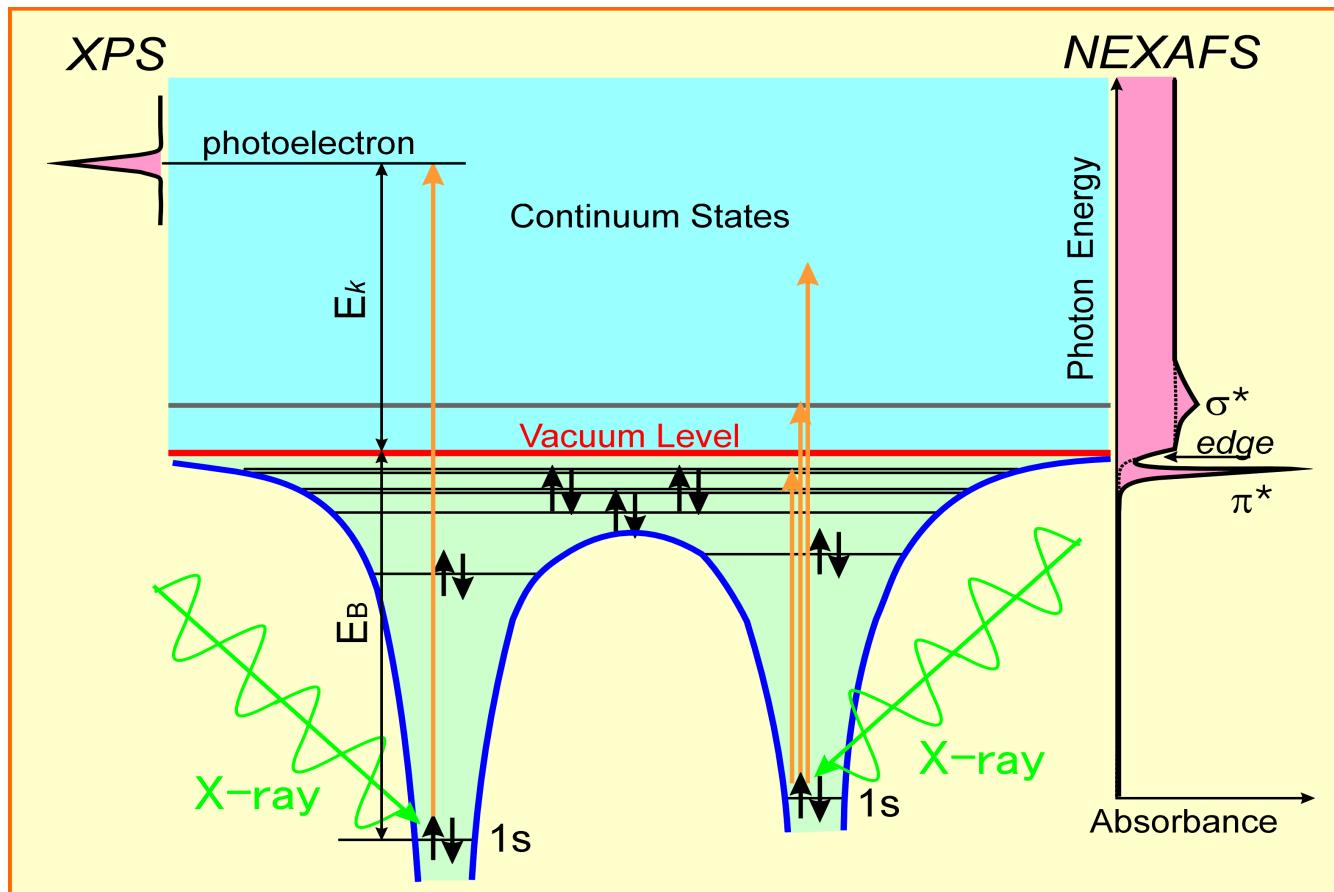
- 空準位のエネルギーと部分状態密度  
⇒ LUMO, LUMO+1・など空軌道の情報
- 空準位への遷移モーメントの方向  
⇒ 吸着分子や固体の配向情報
- ある空準位への遷移モーメントを持つものの量  
⇒ 吸着分子の被覆率

# Basics of NEXAFS

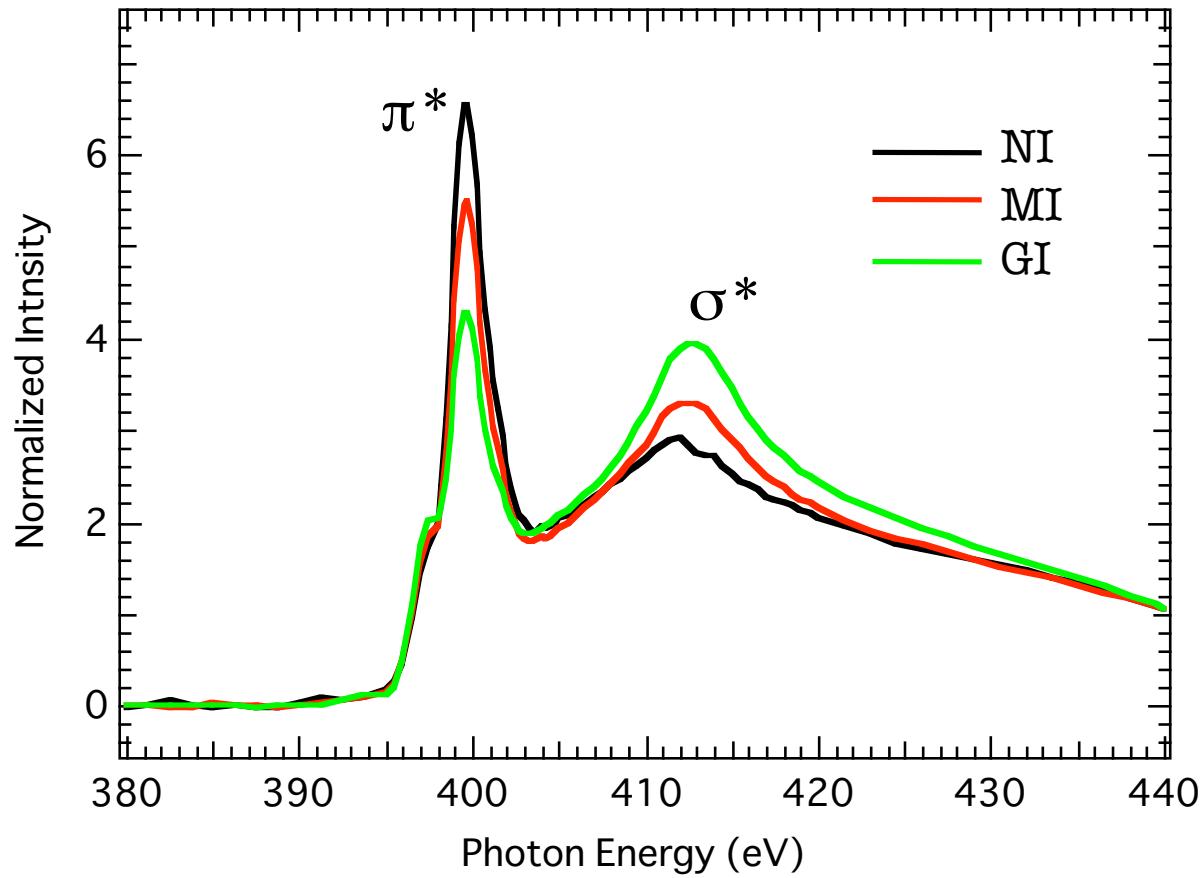
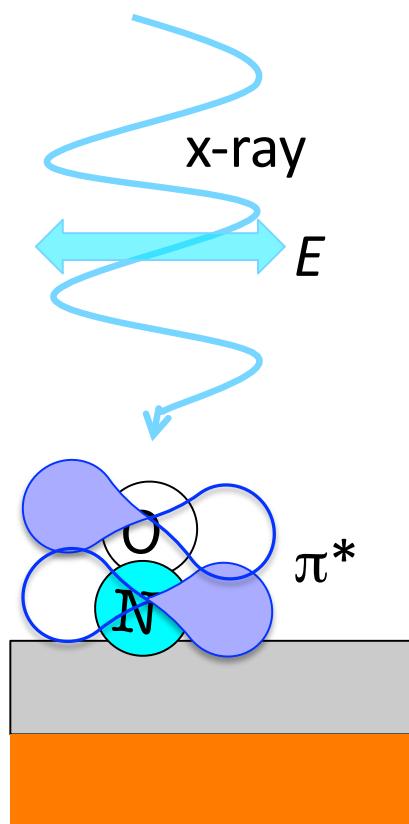
# Near-Edge X-ray Absorption Fine Structure (NEXAFS)

## 特徴

- 元素選択性
- (表面で) 1 ML以下の分子を定量的に観測できる
- 局所的な分子の配向構造が見える (偏光依存性から)
- 局所電子構造が見える (unoccupied states)



# N-K NEXAFS of NO: NO/Fe/Cu(001)

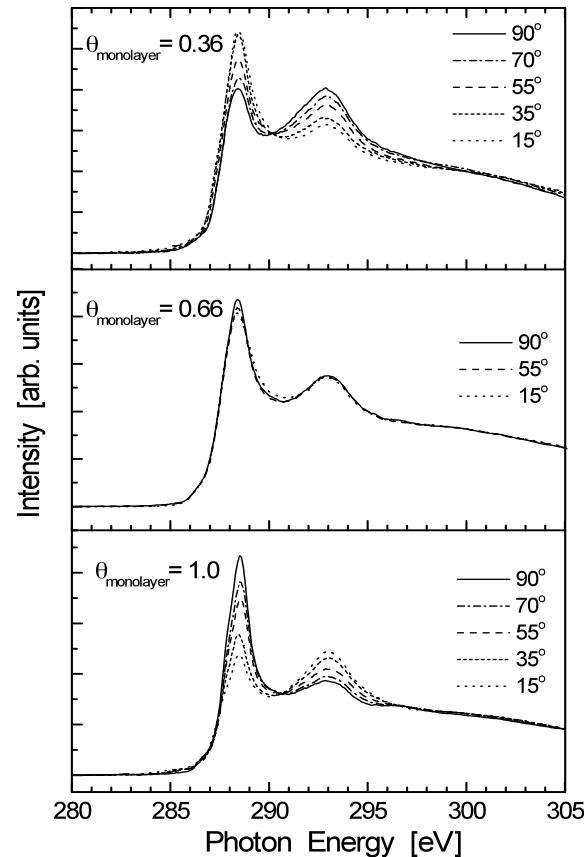


large  $\pi^*$  peak for Normal incidence (NI)

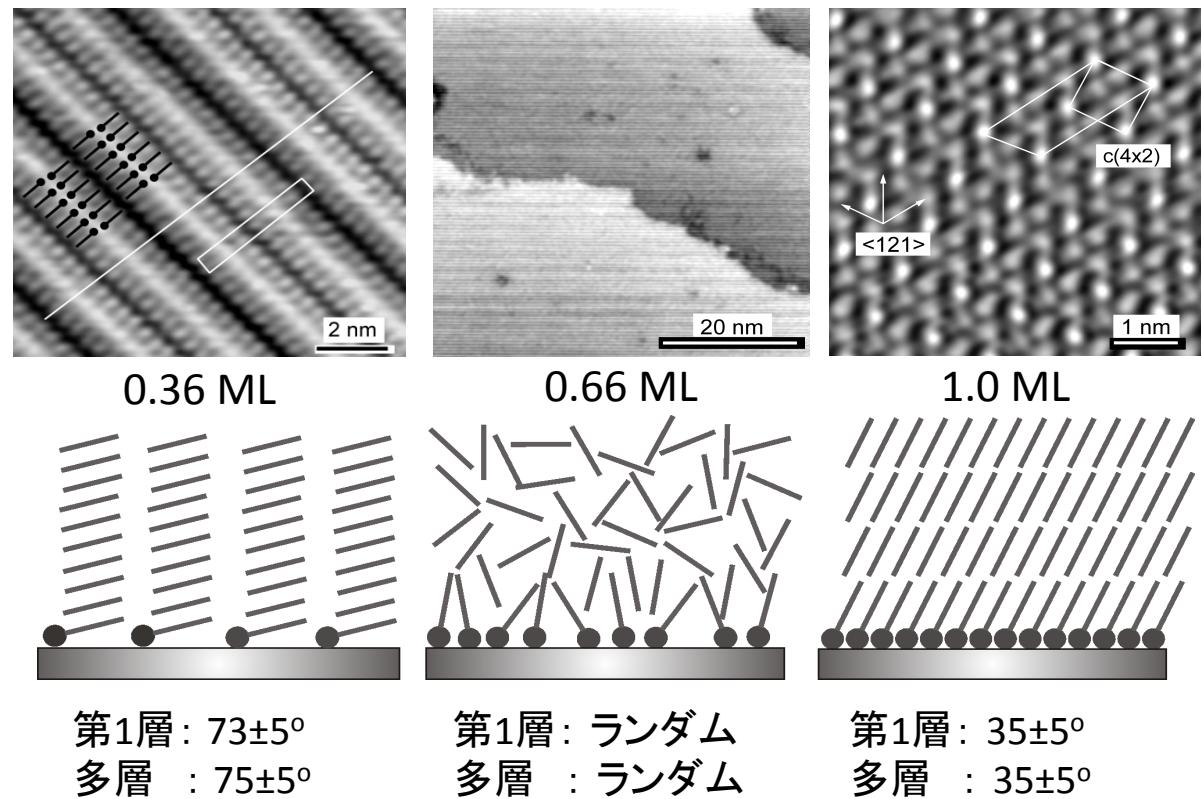
NO molecules: nearly perpendicular to the plane

# NEXAFSの応用例 (吸着分子の配向情報)

多層 $C_6H_{14}$ /单層 $C_6H_{13}S/Au(111)$ に対するC-K NEXAFSによって観測された  
表面第1層をtemplateとする多層配向



表面第1層のチオレート单分子膜のSTM像

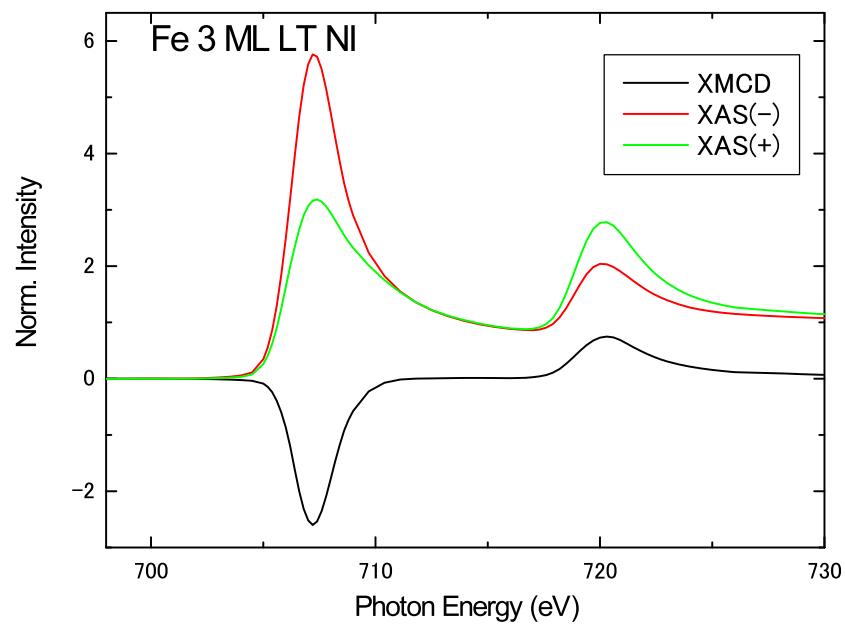


表面第1層の分子密度(配向)を変えたときの  
 $C_6H_{14}/C_6H_{13}S/Au(111)$ に対するC-K NEXAFS

配向モデル

H. Kondoh et al. *Langmuir* **17**, 8178 (2001).

# Basics of XMCD



# XMCDで分かること

元素選択的に

- 磁化の向き
- スピンと軌道の磁気モーメント

# What is XMCD?

- Normal one photon absorption (NEXAFS)
- Absorption spectroscopy **with circularly polarized light**
- Take the **difference** of the “+” and “-” XAS

$$\vec{r} = x\vec{e}_x + y\vec{e}_y + z\vec{e}_z \quad P_1^{(1)} = \vec{e} \cdot \vec{r} = -\frac{1}{\sqrt{2}}(x + iy) = r\sqrt{\frac{4\pi}{3}}Y_1^1 \quad : Right$$
$$\vec{e} = \mp \frac{1}{\sqrt{2}}(\vec{e}_x \pm i\vec{e}_y) \quad P_{-1}^{(1)} = \vec{e} \cdot \vec{r} = \frac{1}{\sqrt{2}}(x - iy) = r\sqrt{\frac{4\pi}{3}}Y_1^{-1} \quad : Left$$

selection rules:

orbital angular momentum quantum number:  $\Delta l = \pm 1$

magnetic quantum number:  $\Delta m_l = +1$  (Right),  $-1$  (Left)

XMCD signal intensity

$$\Delta I = I(+) - I(-)$$

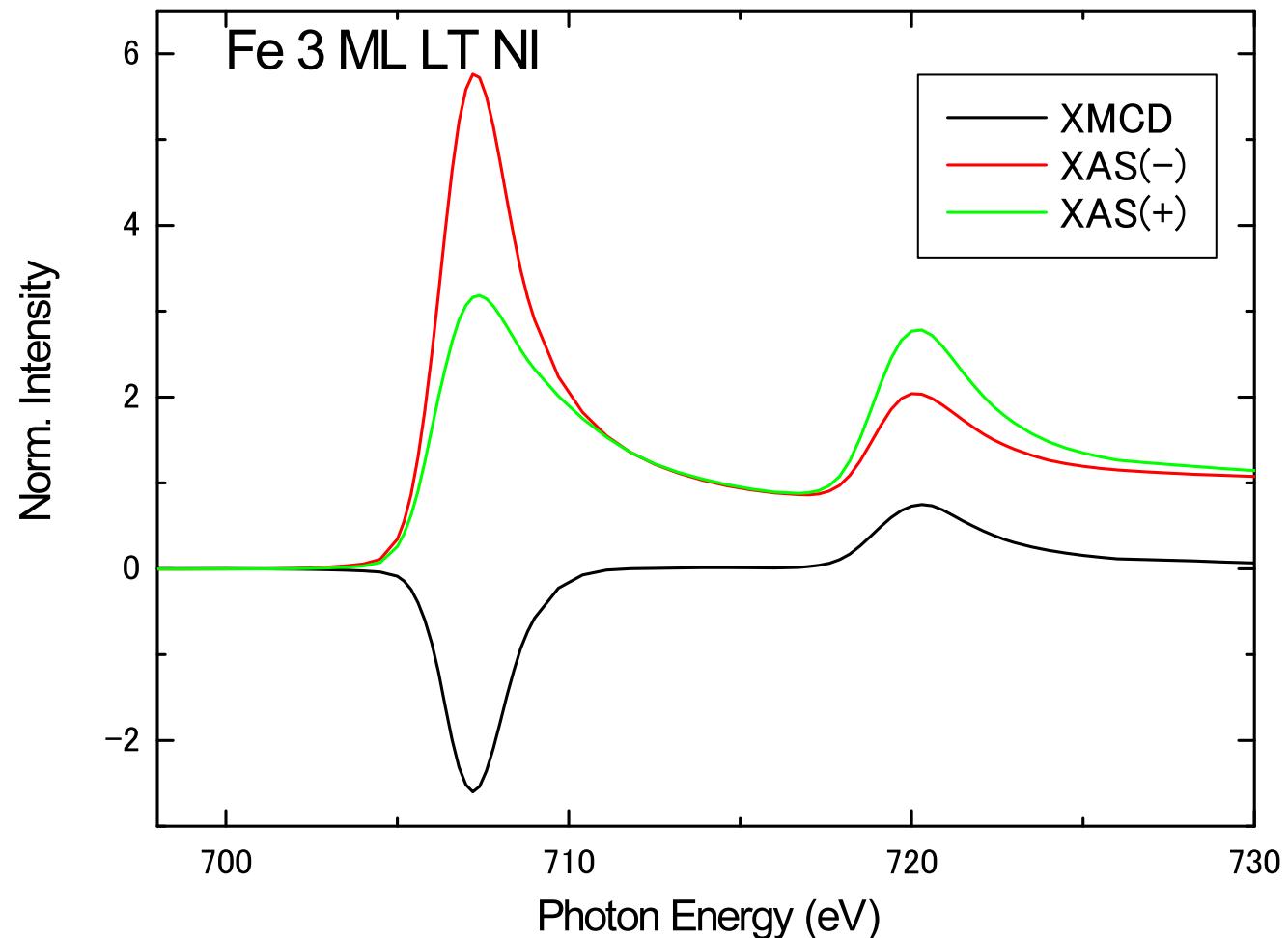
$I(+)$ : XAS with photon spin parallel to majority spin

$I(-)$ : XAS with photon spin antiparallel to majority spin

$$\text{XAS}(+) - \text{XAS}(-) = \text{XMCD}$$

X-ray Absorption Spectrum

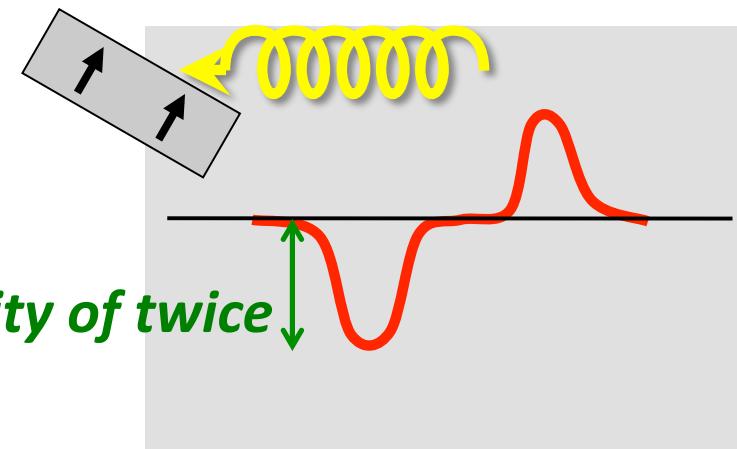
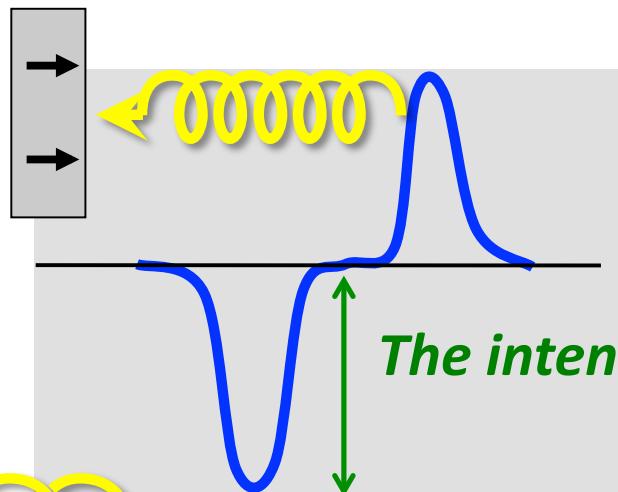
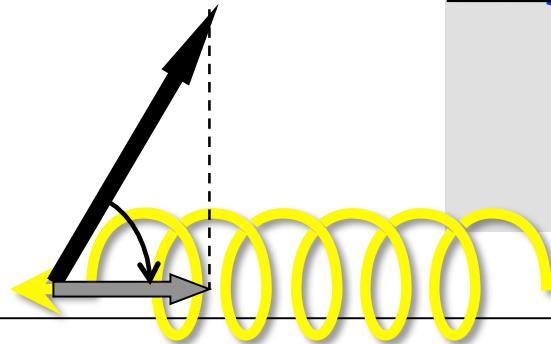
X-ray Magnetic Circular Dichroism



# XMCD spectra and magnetization direction

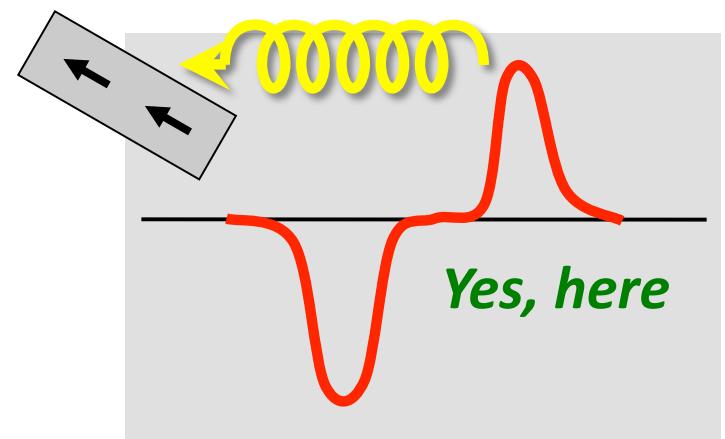
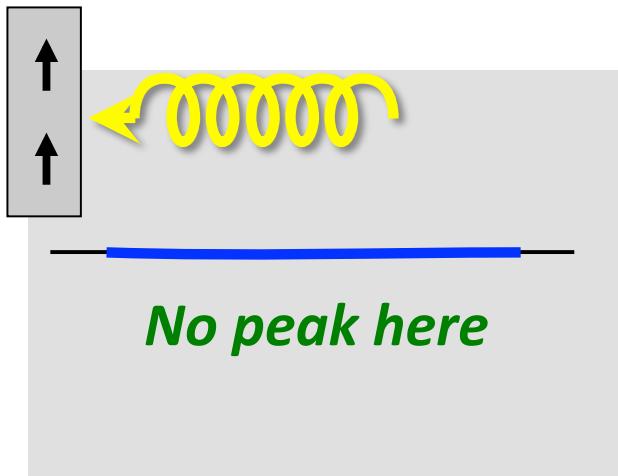
Normal incidence ( $90^\circ$ )    Grazing incidence ( $30^\circ$ )

Perpendicular magnetization

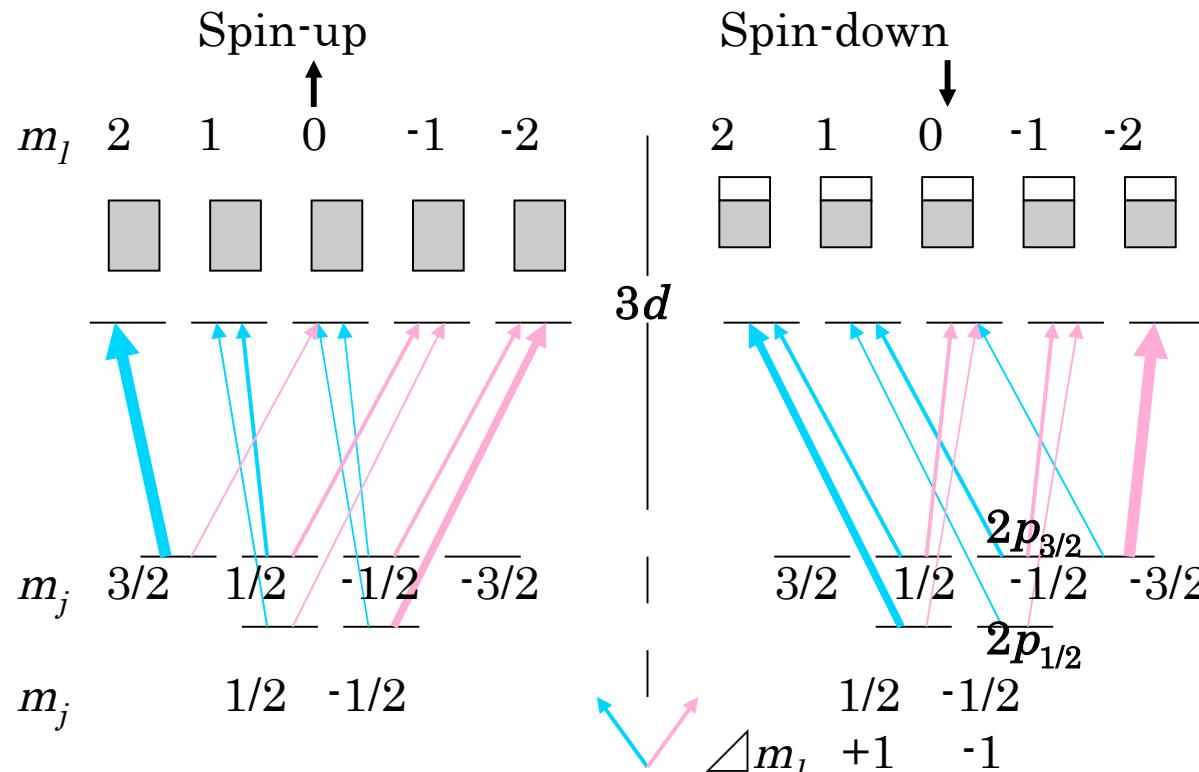


The **cosine component** can be seen.

In-plane magnetization



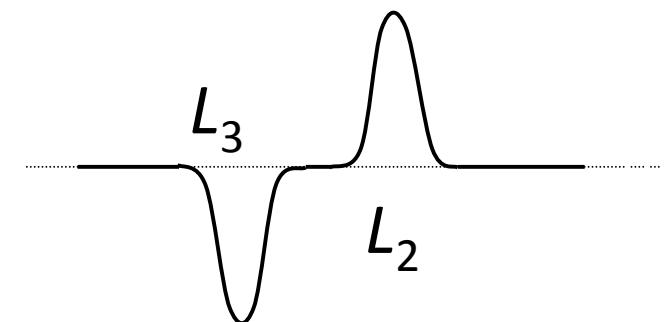
# XMCD: $d$ orbitals without s-o interaction



$d$  orbitals without spin-orbit interaction

Quenched orbital magnetic moment  $\rightarrow$

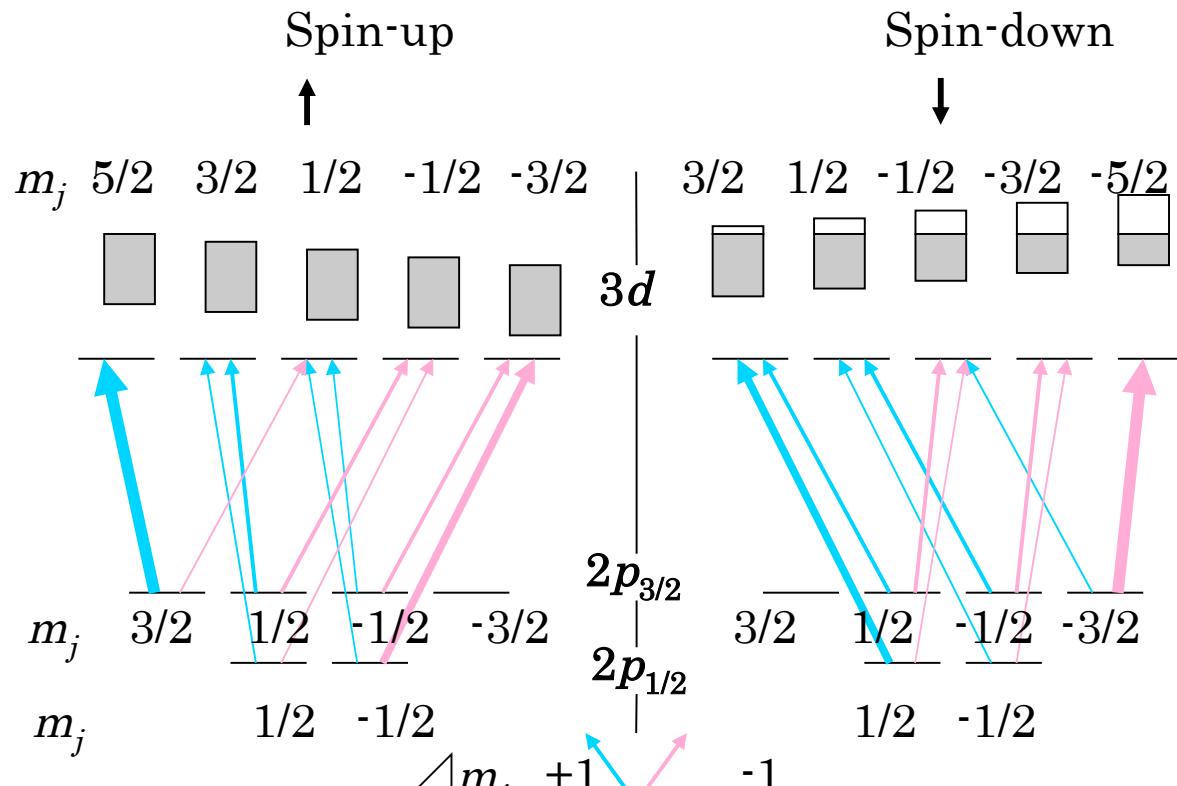
$$|\Delta L_3| = |\Delta L_2|$$



Symmetric shape of XMCD

The same XMCD intensities both at  $L_3$  edge and  $L_2$  edge

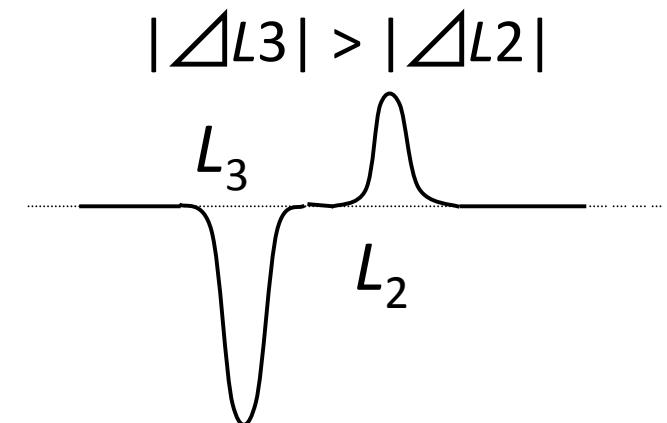
# XMCD: $d$ orbitals with s-o interaction



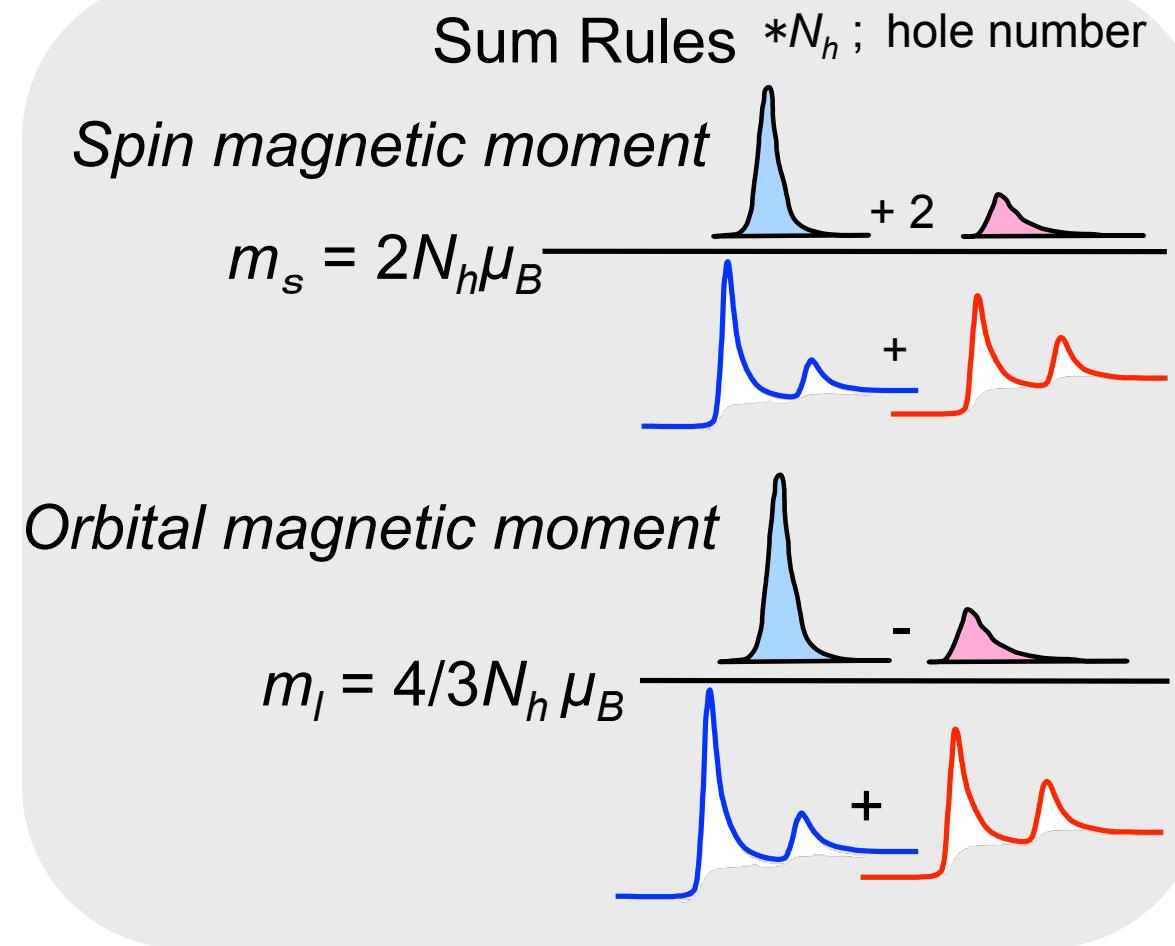
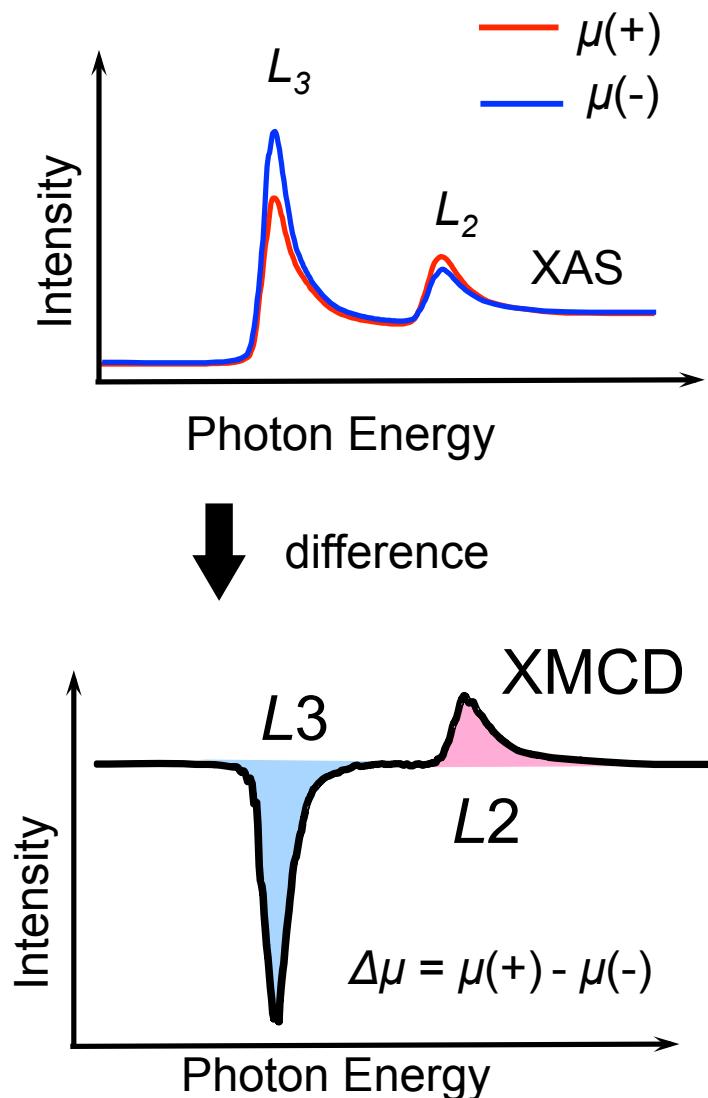
$d$  orbitals with spin-orbit interaction

Survived orbital magnetic moment

→ Asymmetric shape of XMCD

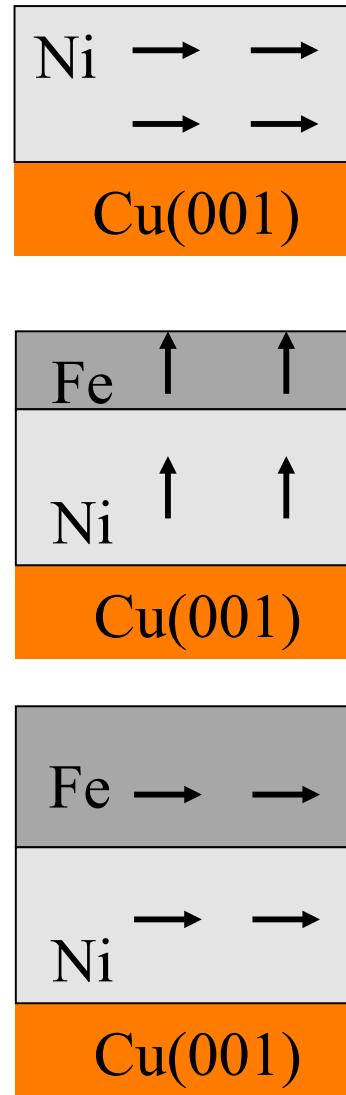
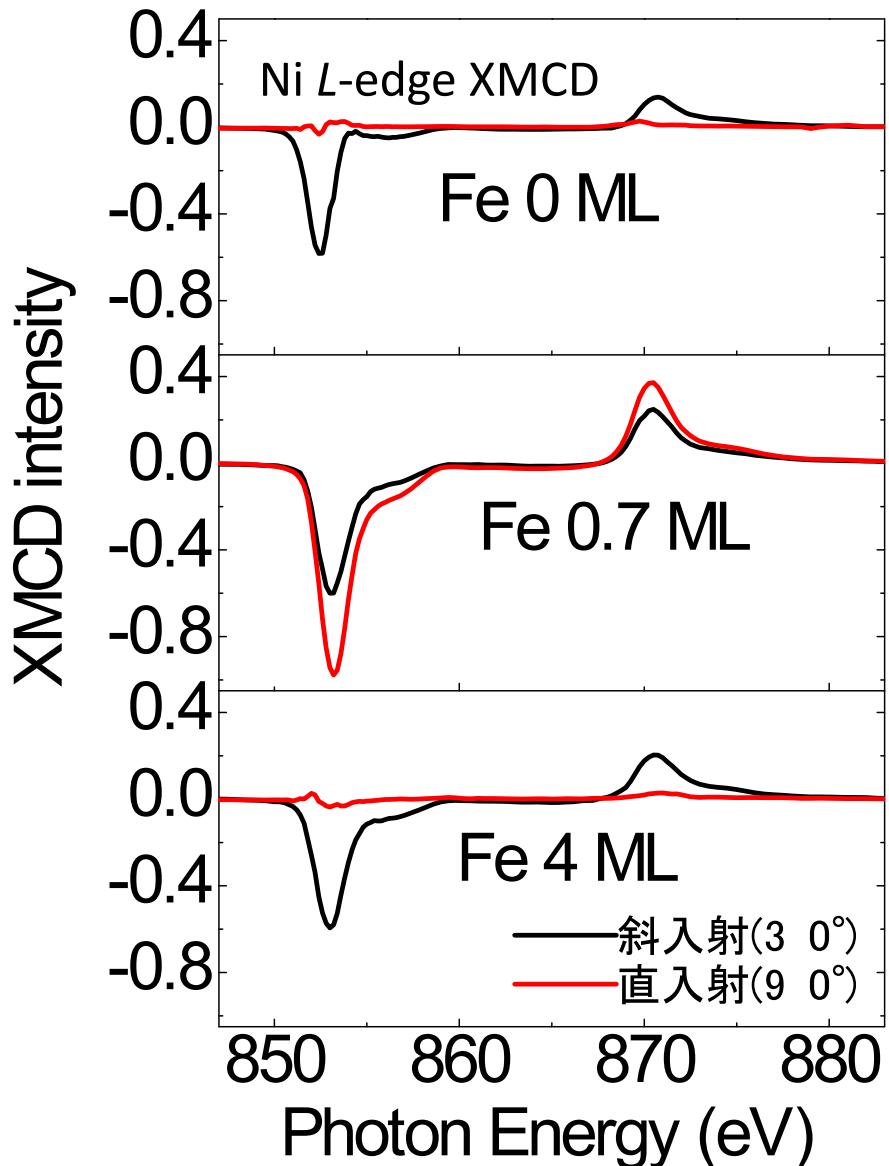


# Sum rules: XMCD spectra and magnetic moments



B. T. Thole, *et al.*, Phys. Rev. Lett. **68**, 1943 (1992)  
 P. Carra, *et al.*, Phys. Rev. Lett. **70**, 694 (1993)

# Ni/Cu(001)にFeを蒸着していくと...



Ni(7.5 ML)/Cu(001)

Fe なし

面内磁化

Fe 0.7 ML

面直磁化

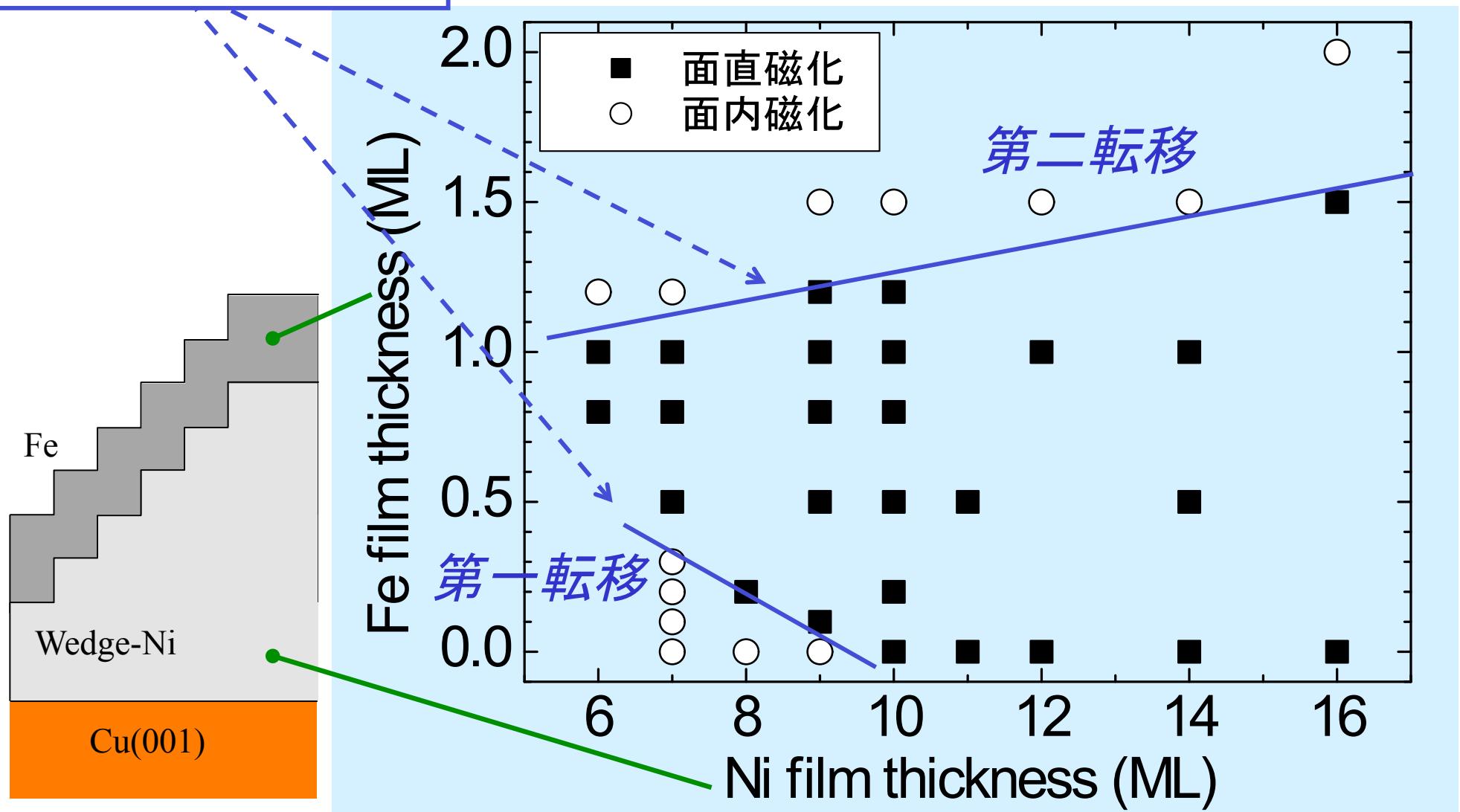
Fe 4 ML

面内磁化

2回の  
スピニ再配列転移

# Fe/Ni/Cu(001)の磁気異方性相図

スピニ再配列転移



# NEXAFS, XMCDでわかること

We can get from...

元素選択的に

NEXAFS:

- ・どんな分子が(表面近傍に)存在するか
- ・その分子がどんな方向を向いているか
- ・その分子がどのくらいあるか

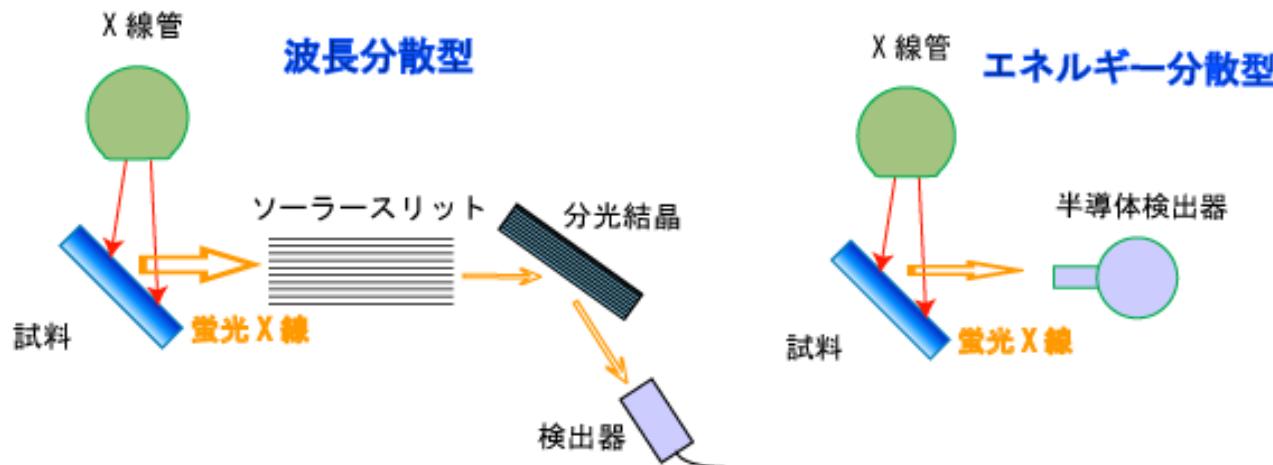
XMCD:

- ・磁化の方向
- ・スピンと軌道の磁気モーメント

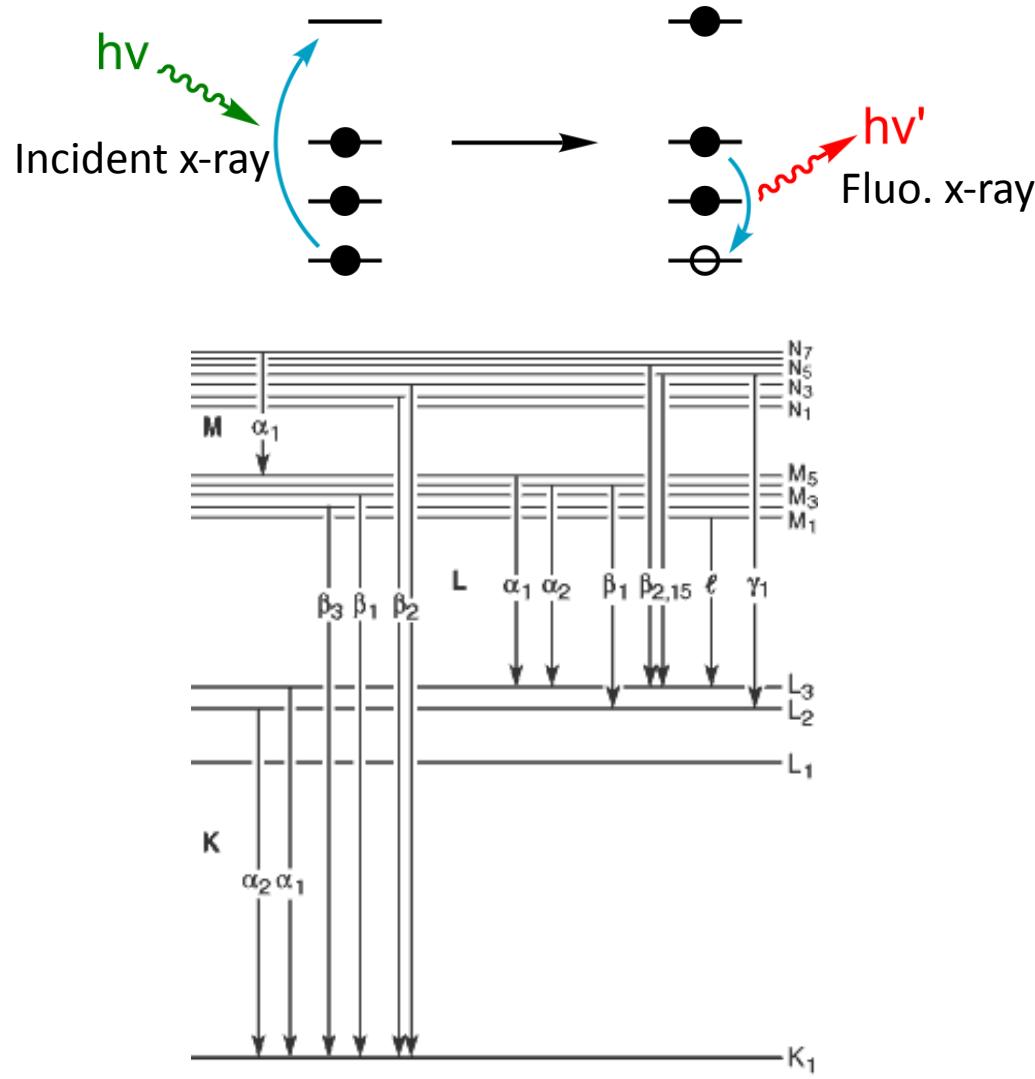
# 蛍光X線分析

(X-ray Fluorescence Analysis, XRF)

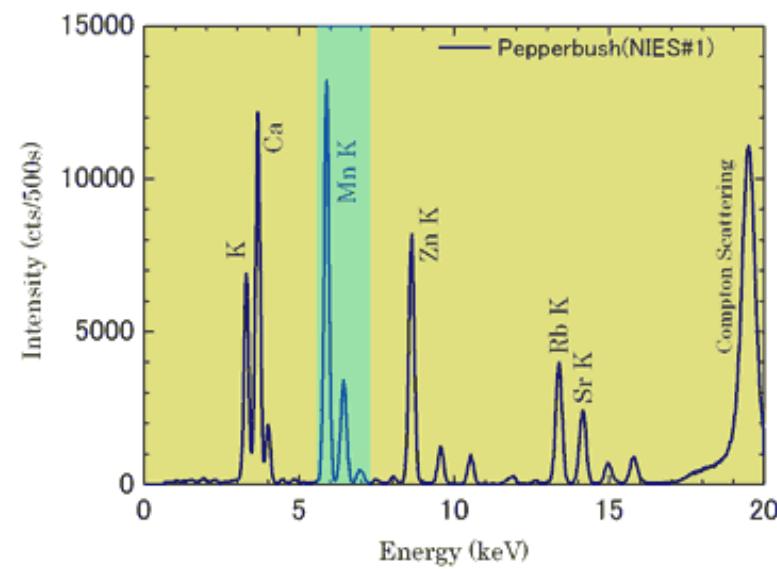
- (1) 試料の化学的処理は不要(非破壊分析)。
- (2) 適用元素はNaからUまでの全元素で、測定時間も短い。多元素分析も可能。
- (3) 分析可能範囲が、1ppm程度から100%までと広い。しかも分析精度が高い。



# Element specific emission: Fluorescent x-ray



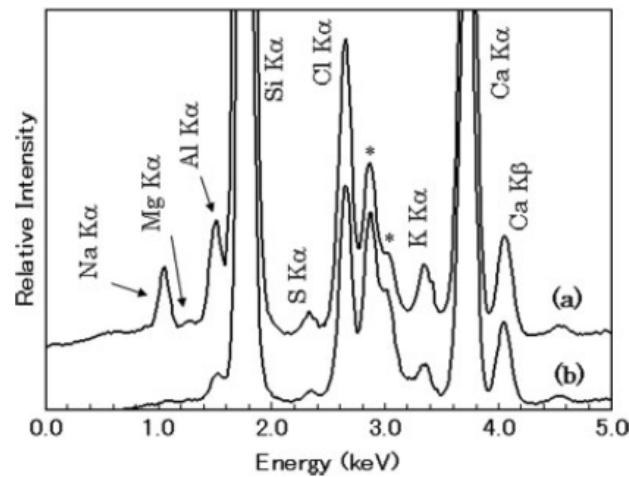
Element	$K\alpha_1$	$K\alpha_2$
22 Ti	4,510.84	4,504.86
23 V	4,952.20	4,944.64
24 Cr	5,414.72	5,405.509
25 Mn	5,898.75	5,887.65
26 Fe	6,403.84	6,390.84
27 Co	6,930.32	6,915.30
28 Ni	7,478.15	7,460.89
29 Cu	8,047.78	8,027.83
30 Zn	8,638.86	8,615.78



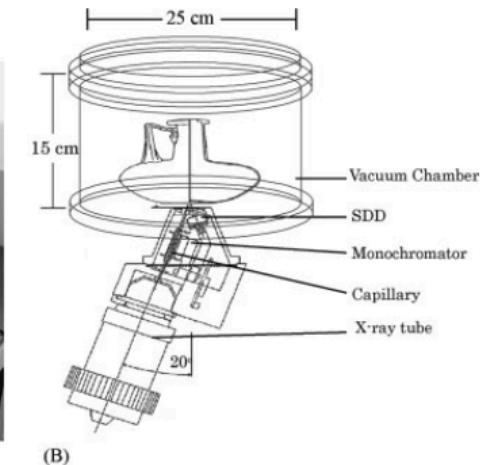
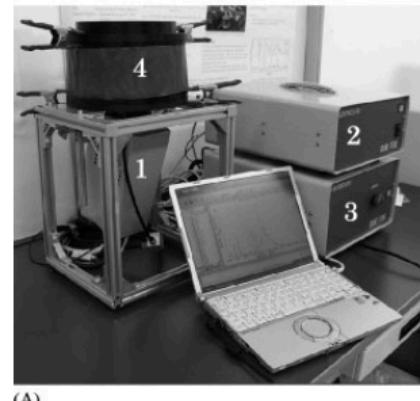
# XRFを使った研究例: 古代のガラス

Archaeological analysis of Roman glass excavated from Zadar, Croatia, by a newly developed portable XRF spectrometer for glass

K. Tantrakarn,<sup>a</sup> N. Kato,<sup>a</sup> A. Hokura,<sup>a</sup> I. Nakai,<sup>a\*</sup> Y. Fujii<sup>b</sup> and S. Gluščević<sup>c</sup>



各元素の含有量がわかる



$\text{Na}_2\text{O}$ ,  $\text{MgO}$ ,  $\text{Al}_2\text{O}_3$ ,  $\text{PdO}$ ,  $\text{CuO}$ , ...

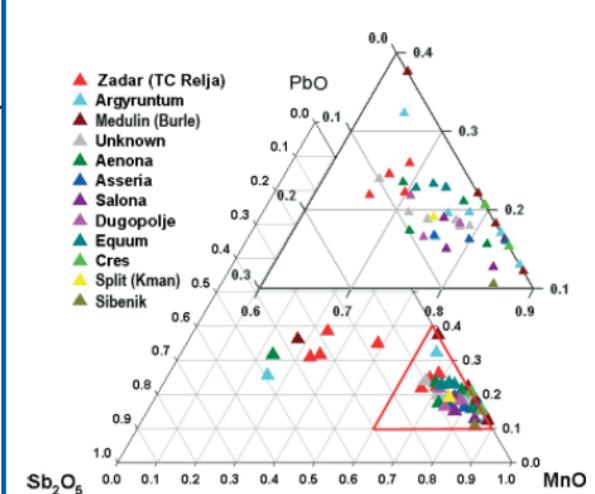




数十%からppmという幅広い濃度で分析できる

Table 3. Glass types and their average chemical compositions

	Bell-shaped flask		Depression flask		Square jug		Cinerary urn		Glass ingot
	Mn decolorizers N = 40	Sb decolorizers N = 8	Mn decolorizers N = 15	Sb decolorizers N = 4	Mn decolorizers N = 4	Sb decolorizers N = 3	Mn decolorizers N = 5	Sb decolorizers N = 1	
Na <sub>2</sub> O (wt%)	14.6 ± 4.5	11.5 ± 6.3	16.4 ± 0.6	24.9 ± 5.5	20.0 ± 3.2	19.6 ± 3.9	18.7 ± 5.8	9.2	14.8
MgO (wt%)	0.60 ± 0.06	0.65 ± 0.05	0.59 ± 0.02	0.66 ± 0.02	0.49 ± 0.24	0.09 ± 0.03	0.16 ± 0.24	0.02	0.06
Al <sub>2</sub> O <sub>3</sub> (wt%)	1.28 ± 0.19	1.21 ± 0.33	1.98 ± 0.69	1.73 ± 0.17	1.26 ± 0.17	1.10 ± 0.05	1.10 ± 0.13	1.30	1.11
K <sub>2</sub> O (wt%)	0.19 ± 0.06	0.20 ± 0.06	0.23 ± 0.11	0.27 ± 0.02	0.26 ± 0.08	0.26 ± 0.04	0.19 ± 0.06	0.22	0.15
CaO (wt%)	4.25 ± 0.50	3.58 ± 0.53	3.96 ± 0.33	4.64 ± 0.04	4.16 ± 0.44	3.68 ± 0.22	3.85 ± 0.54	3.22	3.32
MnO (wt%)	1.10 ± 0.15	1.05 ± 0.18	1.00 ± 0.12	1.05 ± 0.10	0.70 ± 0.09	0.80 ± 0.05	0.15 ± 0.01	0.15	0.82
Fe <sub>2</sub> O <sub>3</sub> (wt%)	0.29 ± 0.05	0.32 ± 0.05	0.30 ± 0.05	0.39 ± 0.01	0.32 ± 0.08	0.34 ± 0.01	0.27 ± 0.06	0.30	0.24
PbO (ppm)	100 ± 30	360 ± 100	190 ± 70	470 ± 30	200 ± 190	1620 ± 360	250 ± 230	1000	90
SrO (ppm)	680 ± 90	580 ± 80	690 ± 20	700 ± 30	635 ± 85	560 ± 40	580 ± 50	530	550
CuO (ppm)	1100 ± 240	1220 ± 300	1410 ± 120	1640 ± 40	1480 ± 800	2070 ± 400	1640 ± 1320	1740	1020
Zr (ppm)	3580 ± 220	3520 ± 370	3800 ± 60	3840 ± 160	3630 ± 280	3560 ± 70	3550 ± 100	3700	3510
Sb <sub>2</sub> O <sub>3</sub> (ppm)	1650 ± 1270	26300 ± 9800	2560 ± 1790	22500 ± 6300	2200 ± 1090	23500 ± 1900	2790 ± 2240	22000	1390

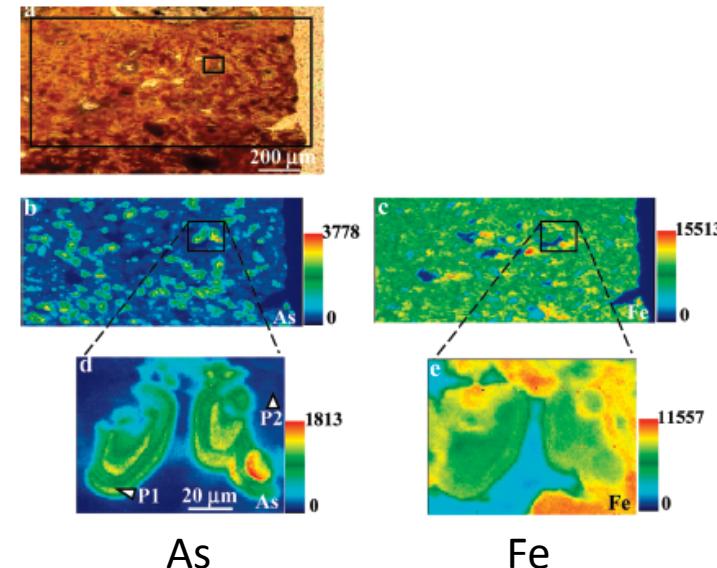
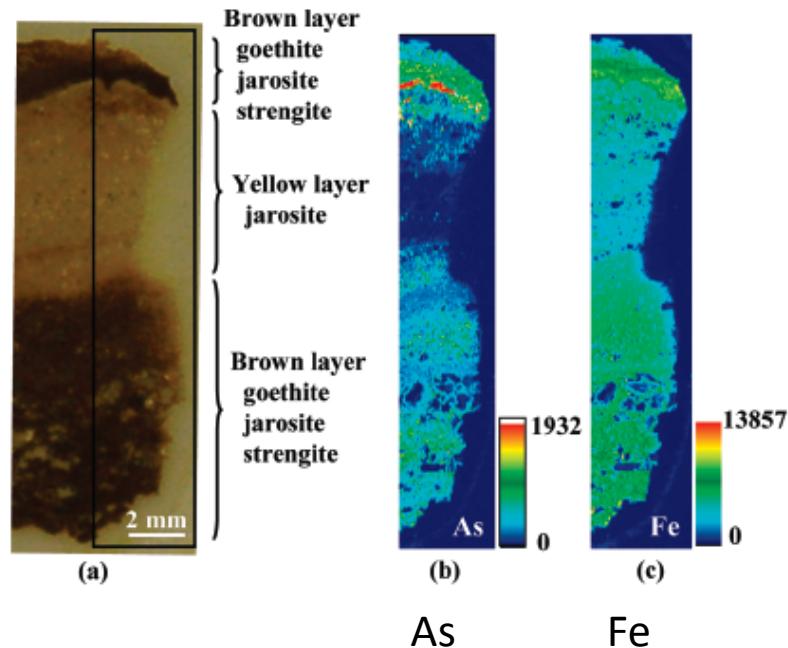


# $\mu$ -XRFを使って元素マッピングの例

## Chemical Speciation of Arsenic-Accumulating Mineral in a Sedimentary Iron Deposit by Synchrotron Radiation Multiple X-ray Analytical Techniques

SATOSHI ENDO,<sup>†</sup> YASUKO TERADA,<sup>‡</sup>  
YASUHIRO KATO,<sup>§</sup> AND IZUMI NAKAI<sup>\*,†</sup>

鉱物中の元素の濃度分布が見える

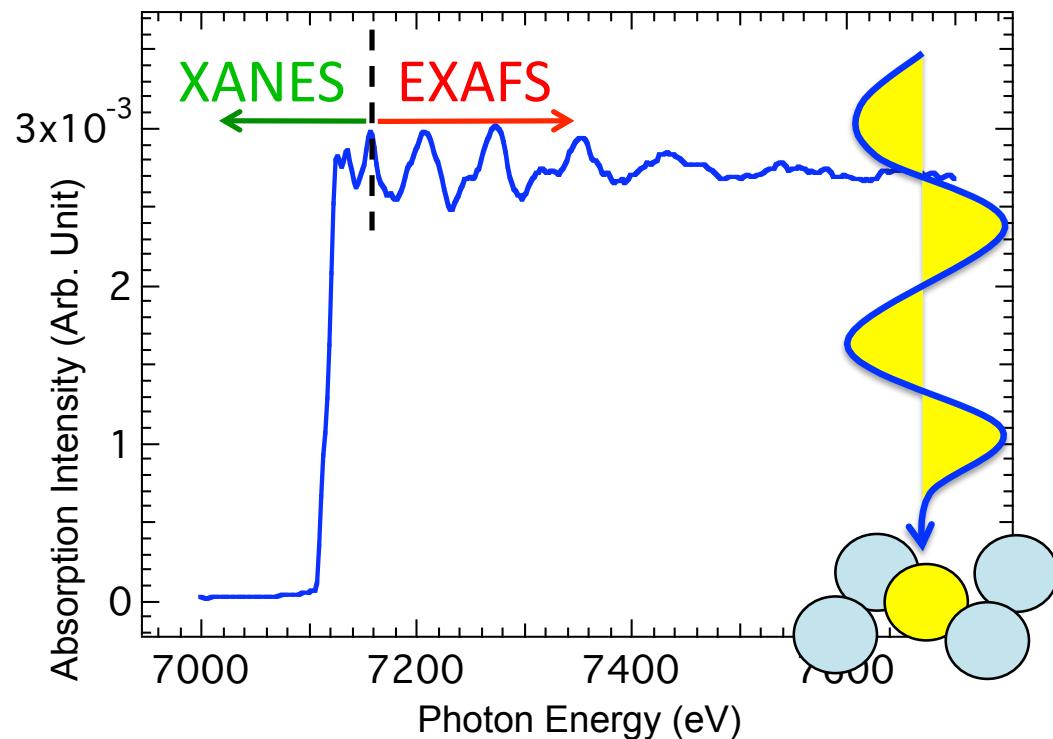


# XAFSって？ -XAFSデータが含むもの-

X-ray Absorption Fine Structure  
(X線吸収微細構造)

電子状態  
(価数)  
対称性

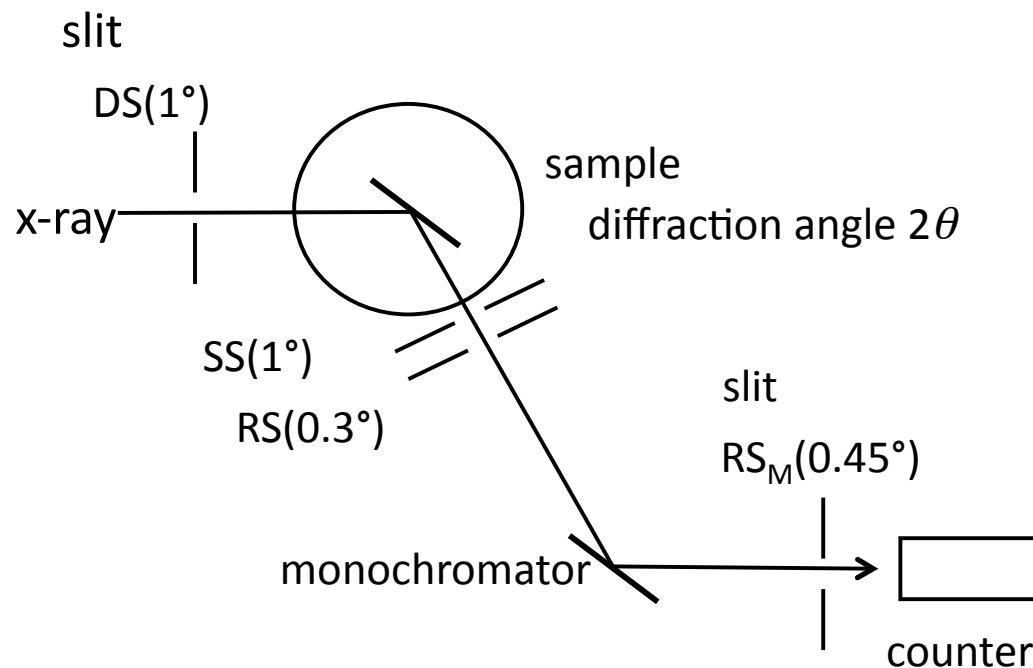
吸收原子と周辺の散乱原子との結合距離  
周辺原子の数(配位数)、種類  
周辺原子の分布の様子、熱振動



元素選択的に情報が得られる  
局所構造を観測する  
結晶のような周期性がなくてもOK  
固相、液相、気相、何でも測定できる

XANES: X-ray Absorption Near Edge Structure  
EXAFS: Extended X-ray Absorption Fine Structure

# X-ray diffraction (XRD)



a machine for XRD measurements

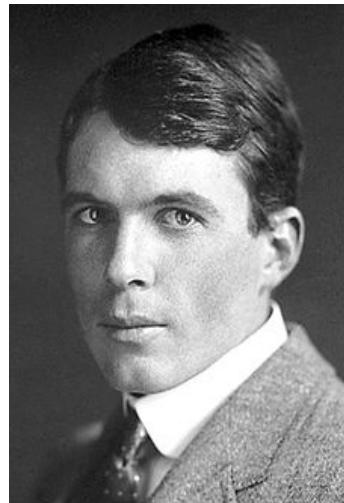


RINT-TTR III, Rigaku

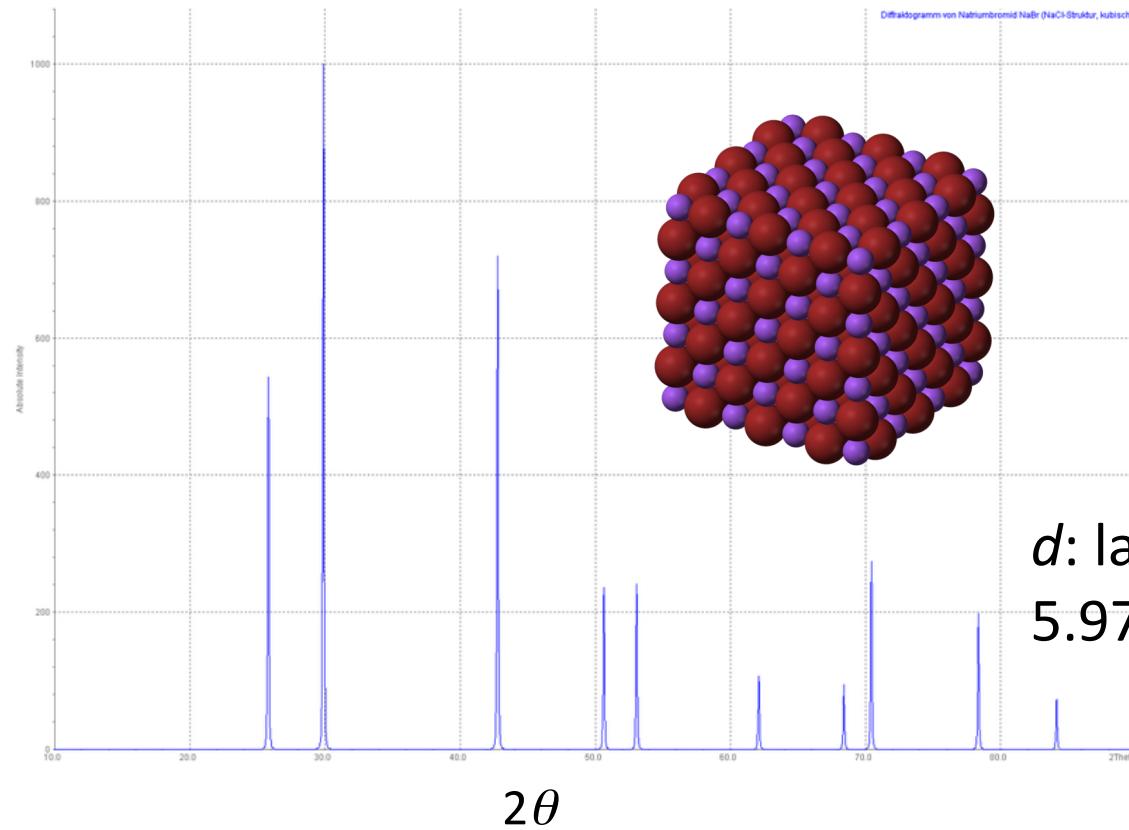
# an XRD spectrum of NaBr

*What is the ruler here?*

**The wave length of the x-ray is used as a ruler  
to measure the lattice constant.**



W. L. Bragg  
(1890-1971)



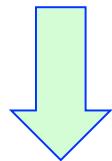
Bragg's law  
 $2d\sin\theta = n\lambda$

$d$ : lattice constant  
5.97 Å

***Long range order is required for XRD measurements.***

# 結合距離でなぜX線なのか？

モノの長さを測る時、どうする？



定規： 目盛りがあって、好きな長さが測れる。

定規がなかったら？

背の高さ、腕を広げた長さ、手の大きさ、...などを使う

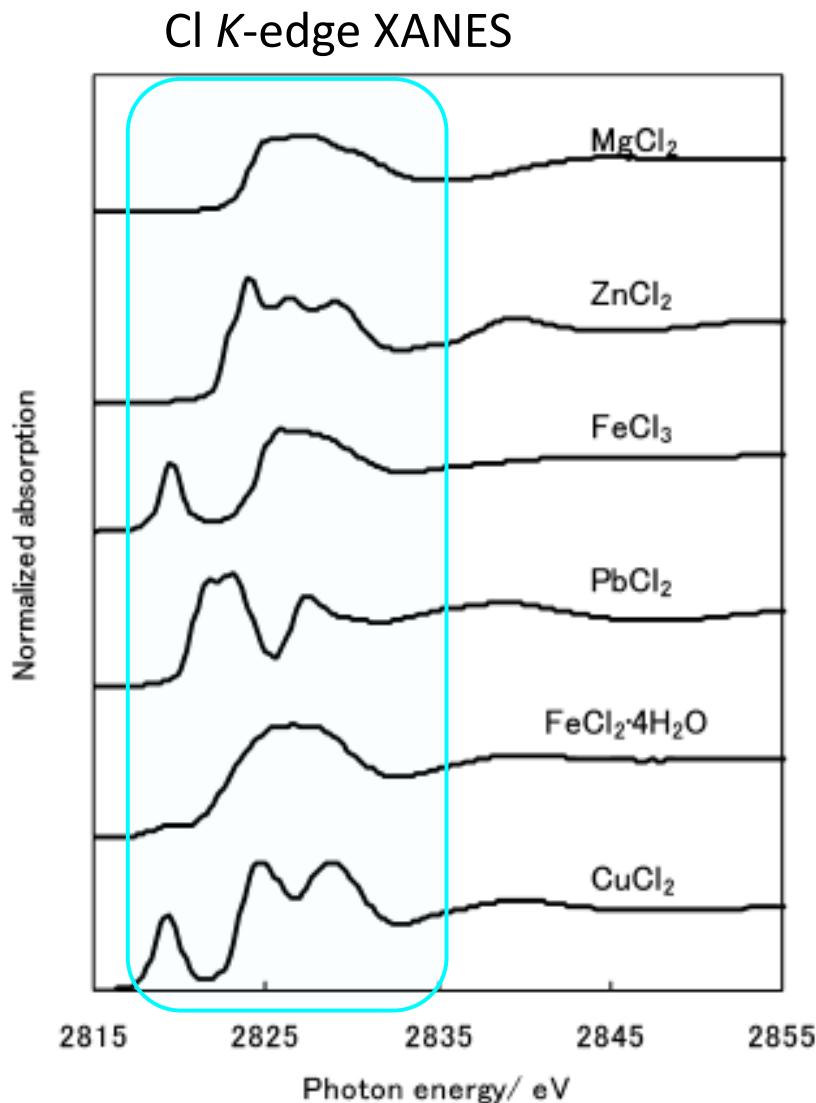
測りたいモノによって、適した基準のモノがある

(背の高さでペンの長さは測らない)

測りたいモノ： 結晶周期、原子間距離、...

適した基準のモノ： X線の波長、電子の波動性、...

# XANES tells us what your sample is.

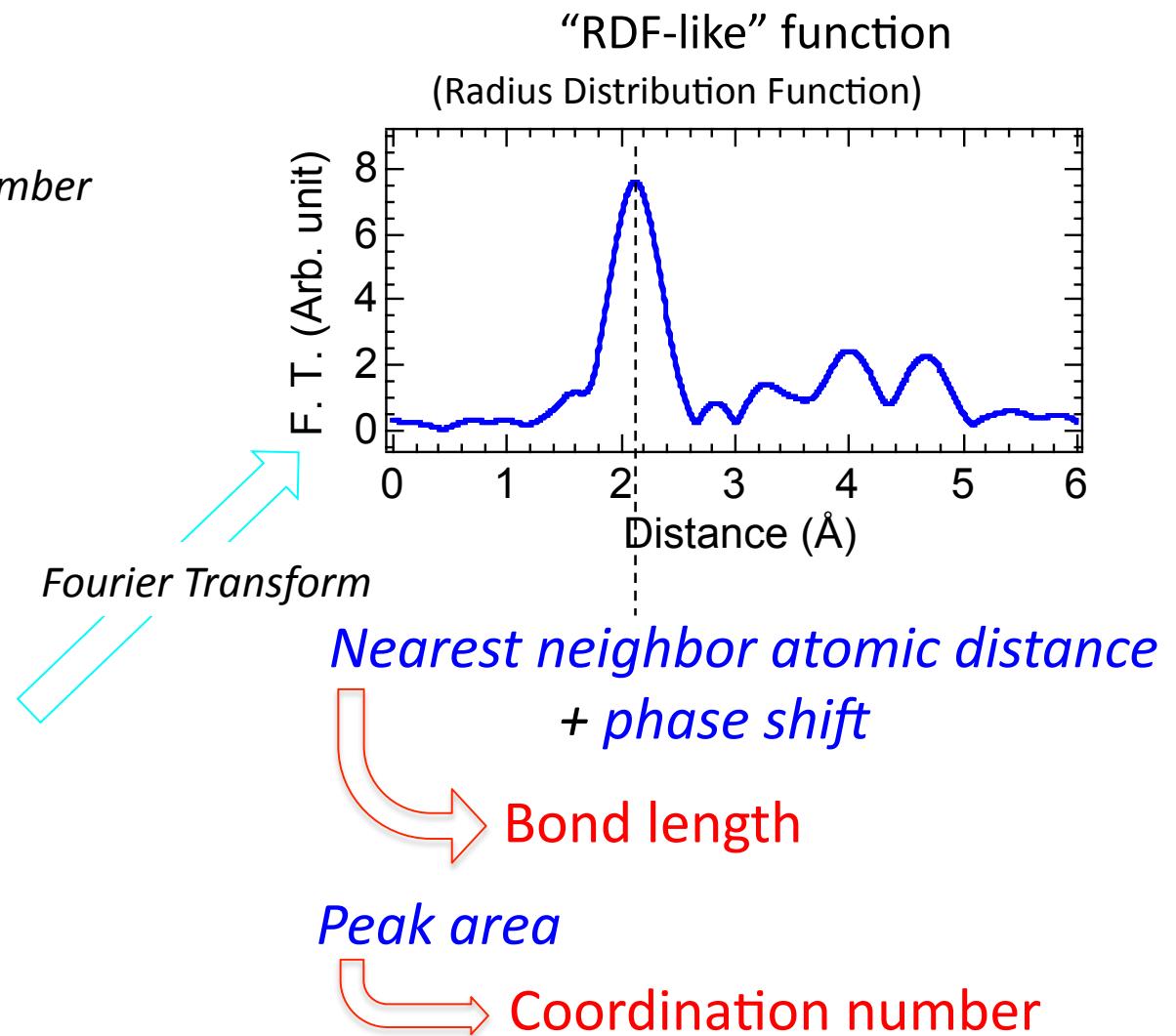
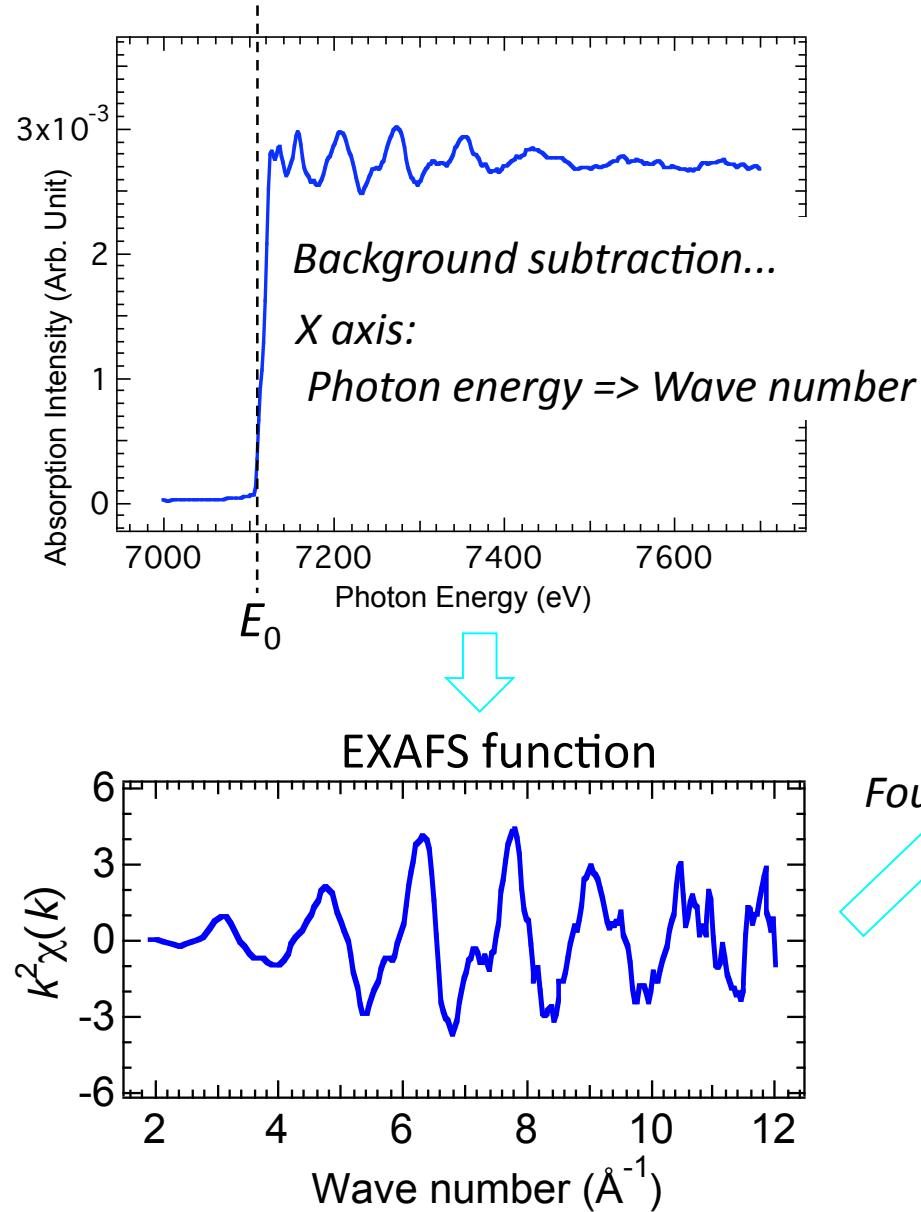


All these are metal chlorides.

But you can see some specific features in each spectrum.

So you would recognize what your sample is.

# How to Obtain Bond Length by EXAFS

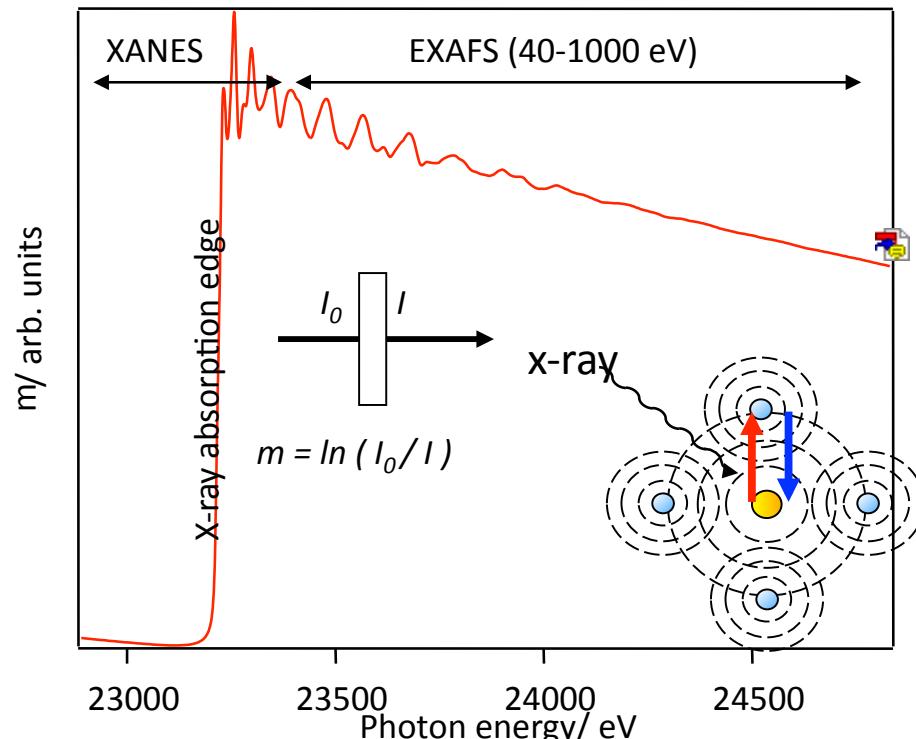


# Simple things XAFS spectra give us

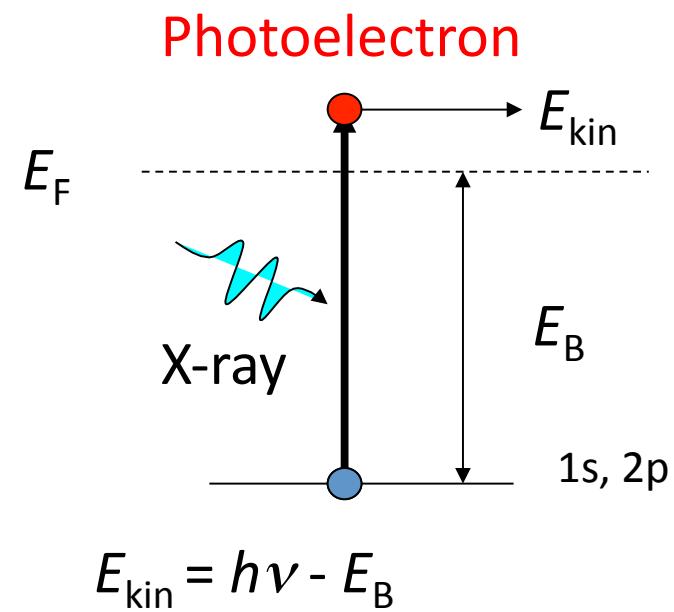
- XANES gives us... with element specificity
  - Valence state
    - We can determine our sample as a certain molecule or material.
  - Symmetry
- EXAFS gives us...
  - Bond length
    - A local structure is given.
    - Crystallinity, or long range order is not required.
  - Coordination number (CN)
    - Simply, the number of atoms around the atom.
    - CN enables us to estimate sizes of nano clusters.

# XAFS

- ✓ X-ray Absorption Fine Structure(XAFS)
  - ✓ XANES(X-ray Absorption Near Edge Structure)
  - ✓ EXAFS(Extended X-ray Absorption Fine Structure)

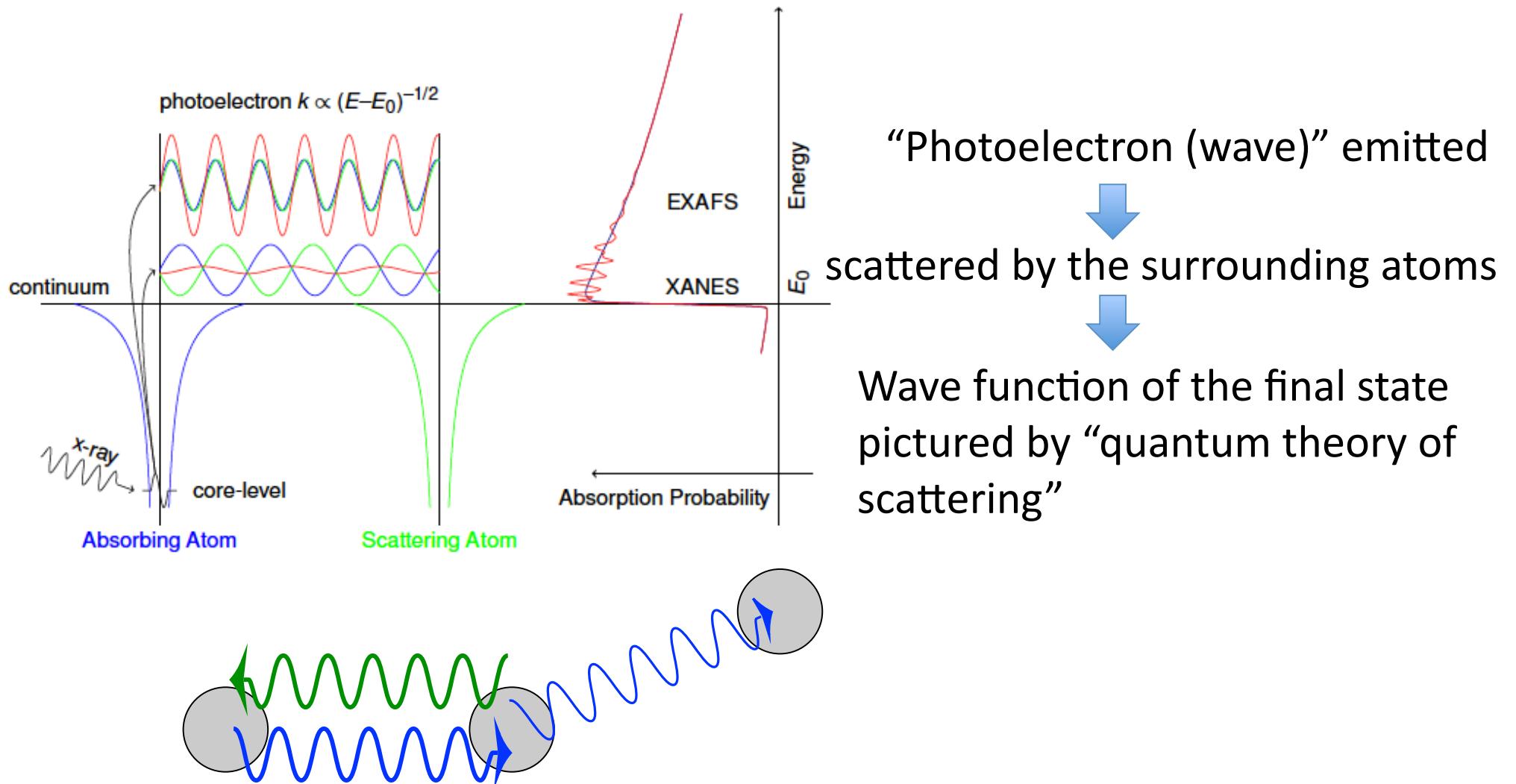


X-ray absorption spectrum



1s electron *K* shell  
2p electron *L* shell

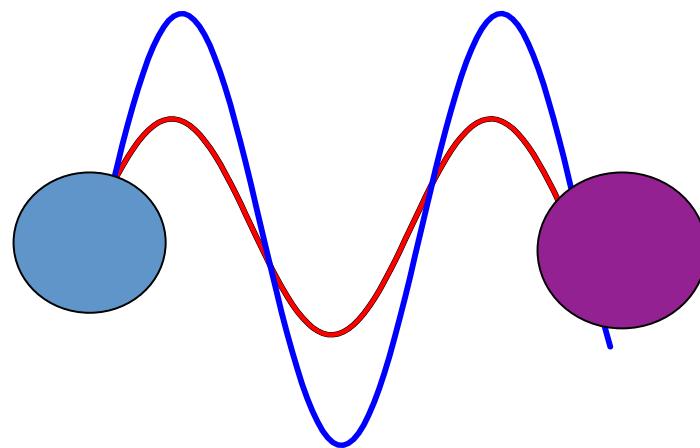
# Picture of the wave function of final state in EXAFS



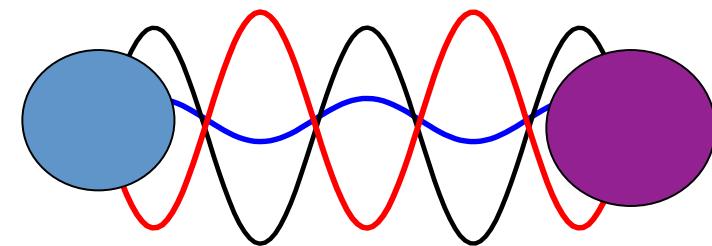
# Scattering of electron and interference

$$\frac{\hbar^2 k^2}{2m} = E - E_0$$

$K$  : wave vector  
 $\hbar$  : Plank Const.  
 $E$ : Photon energy  
 $E_0$  : threshold (edge)

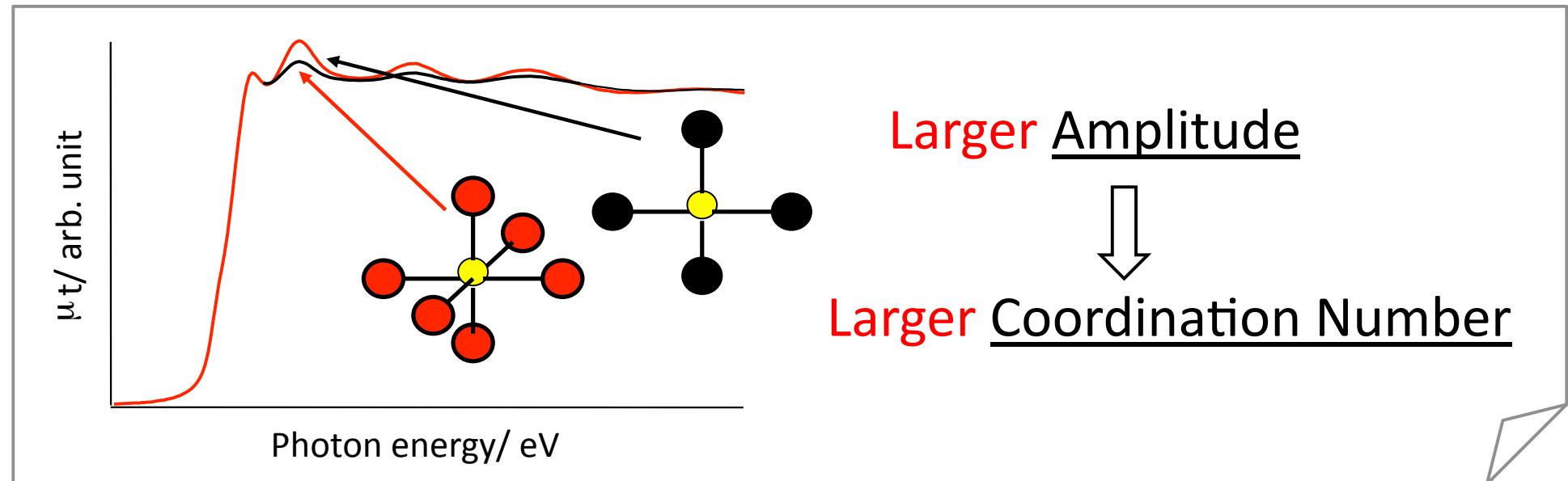
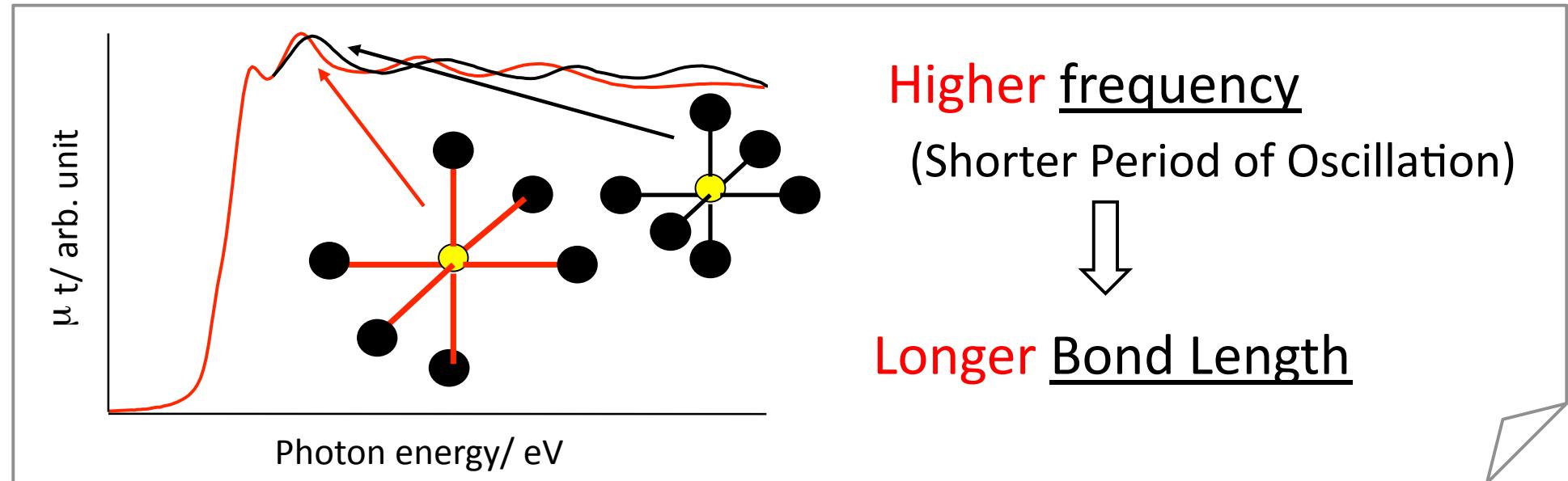


Enhancement

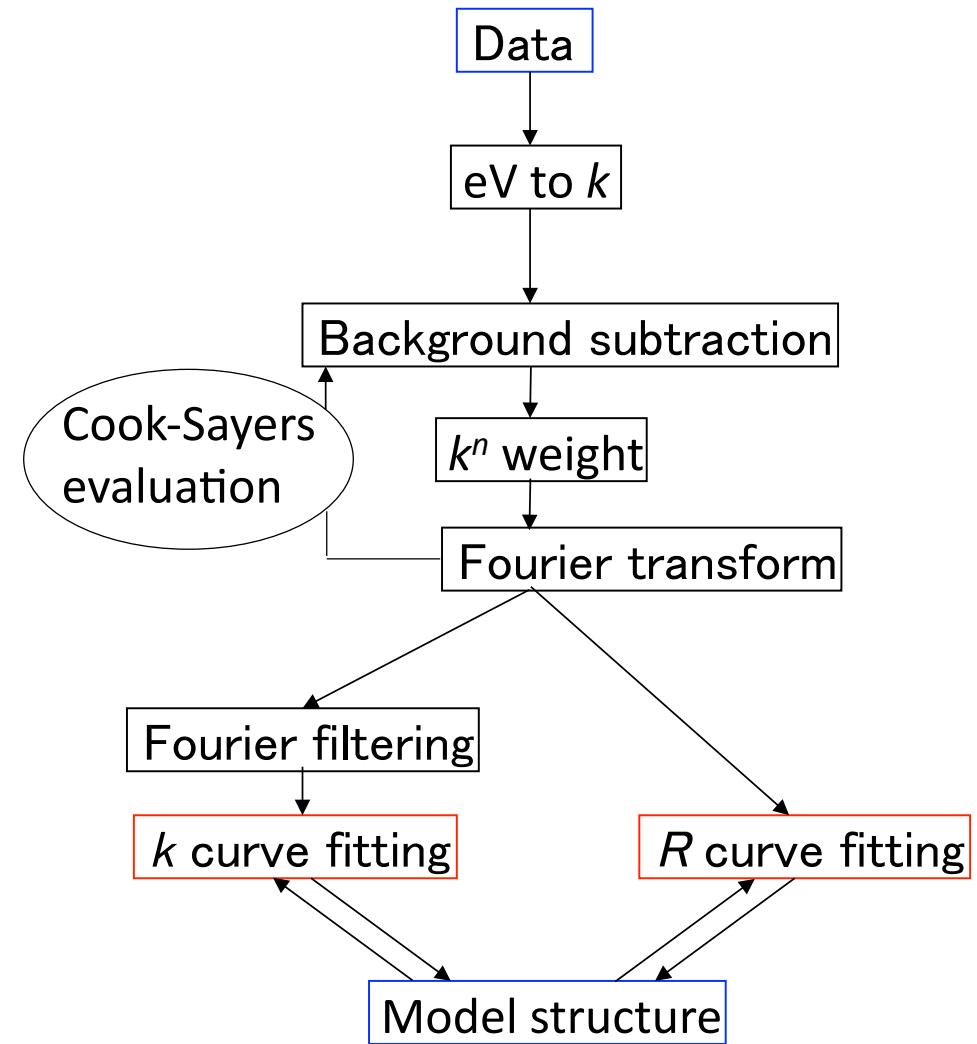
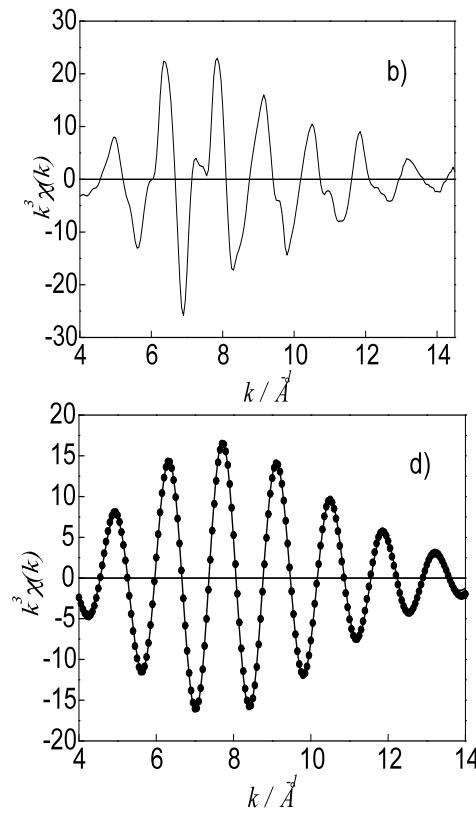
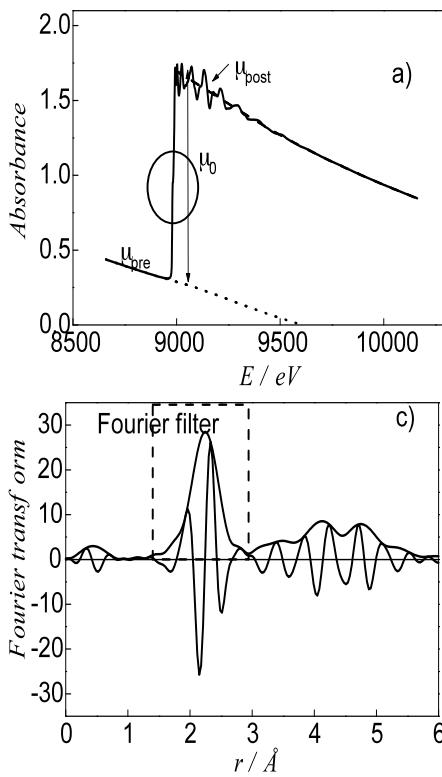


suppression

# Bond length and Coordination number



# Sketch of XAFS analysis



# The EXAFS equation

1. leaving the absorbing atom

2. scattering from the neighbor atom

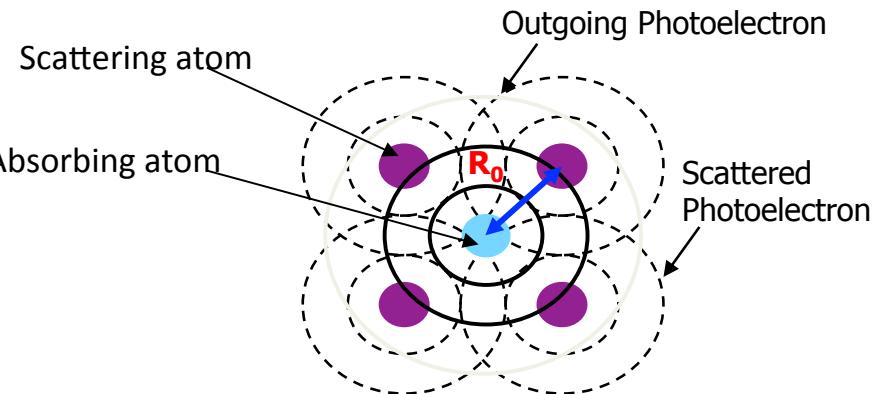
3. returning to the absorbing atom

XAFS oscillation      Absorbance      Smooth background

$$\chi(k) = \frac{\mu(E) - \mu_s(E)}{\mu_0(E)} = S_0^2 \sum_i \frac{N_i F_i(k_i)}{k_i r_i^2} e^{-2k_i^2 \sigma_i^2} \sin(2k_i r_i + \phi_i(k_i))$$

Edge-jump

$$k = \sqrt{2m_e(E - E_0)/\hbar}$$



Theoretically or empirically derived  
Parameters

$F_i$  : Backscattering amplitude

$* e^{-2r_i/\lambda(k_i)}$

$\phi_i$  : Phase shift

Curve-Fitting Parameters

$N_i$  Coordination number

$\sigma_i^2$  DWfactor

$E_0$  energy shift

$r$  distance

# Fermi's Golden Rule to express $\mu$ of XAFS

↙ { Born-Oppenheimer approximation  
velocity of nuclear motion << that of electronic motion  
(due to the high ratio between nuclear and electronic masses)  
Time-dependent Perturbation theory

## Fermi's Golden Rule

$$\mu \propto \sum_f \left| \langle \Psi_f | H' | \Psi_i \rangle \right|^2 \delta(E_f - E_i - \hbar\omega) \quad ... (1)$$

$$H' = -\frac{e}{mc} A(r) \cdot P \quad \begin{array}{l} \bullet \text{ vector potential of X-ray} \\ \uparrow \\ \bullet \text{ momentum of electron} \end{array}$$
$$A(r) = \hat{e} A_0 e^{ik \cdot r} \quad \begin{array}{l} \bullet \text{ unit vector of electric field} \\ \bullet \text{ position of electron} \\ \bullet \text{ wave number vector of X-ray} \end{array}$$

# One-electron approx. & Dipole approx.

$$\mu \propto \sum_f \left| \langle \Psi_f | H' | \Psi_i \rangle \right|^2 \delta(E_f - E_i - \hbar\omega) \quad \dots(1)$$

One-electron approx.:  $\langle \Psi_f | H' | \Psi_i \rangle \cong \langle \psi_f | H' | \psi_i \rangle$

All-electron wave function  $\Rightarrow$  One-electron wave function

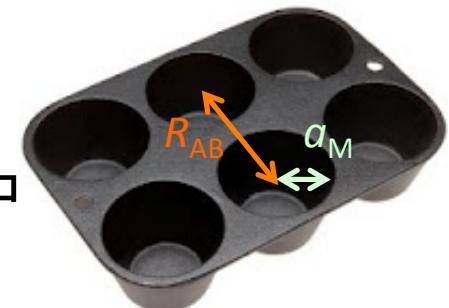
Dipole approx.:  $e^{ik \cdot r} \cong 1$  for  $k \cdot r \ll 1$

$$\mu \propto \sum_f \left| \langle \psi_f | \hat{e} \cdot r | \psi_i \rangle \right|^2 \delta(E_f - E_i - \hbar\omega) \quad \dots(2)$$

fundamental equation to express XAFS

# Assumptions to depict EXAFS eq.

- [1] 一光子吸収
- [2] 一電子近似 & 双極子近似
- [3] ( $K$ 殻) 電子放出 & 一電子散乱近似
- [4]  $kR_{AB} \gg 1$  近似。
  - 各散乱の素過程は主要項で近似(高次項は無視できる)
- [5] Muffin-tinポテンシャル近似
  - ポテンシャルは半径 $a_M$ の球内で球対称で、その中間領域では一定であるとする
- [6] 平面波近似。
  - 最近接原子間距離 $R_{AB}$ に対し、 $a_M \ll R_{AB}$ なので、散乱は平面波で記述できるとする



# Eq. of single scattering EXAFS

$$\chi(k) = -S_0^2 \sum_j \frac{N_j}{kR_j^2} F_j(k) \exp\left(-2\sigma_j^2 k^2\right) \sin\left(2kR_j + 2\delta_{A,1}(k) + \varphi_j(k)\right)$$

“Round trip” of the wave

**Amplitude**      **Oscillation (phase)**

Isolated atom

Atom with neighbor  
Oscillation

Outgoing Photoelectron

Scattered Photoelectron

$R_j$

Fourier Transform...

Bond length  $R_j$ , etc.,

Phase shift  
of absorbing atom  
of scattering atom

E →

(Parameters highlighted by yellow are fitting parameters.)

# de Broglie wave as a Ruler

A particle with the momentum of  $p$   
having the wave character described by the below Eq.

as for Electron

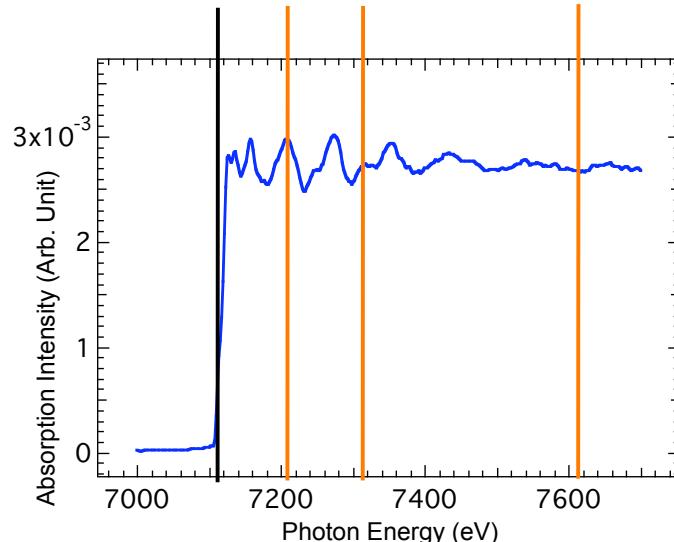
$$\lambda = \frac{h}{p} = \frac{h}{(2m_e eV)^{1/2}}$$

*considering a bond length of  $\sim 2.5 \text{ \AA}$*

100 eV: 1.226 Å	2 waves
200 eV: 0.867 Å	3 waves
500 eV: 0.548 Å	4-5 waves

EXAFS

We use **de Broglie wave of electron** as a **Ruler**, in order to measure bond length

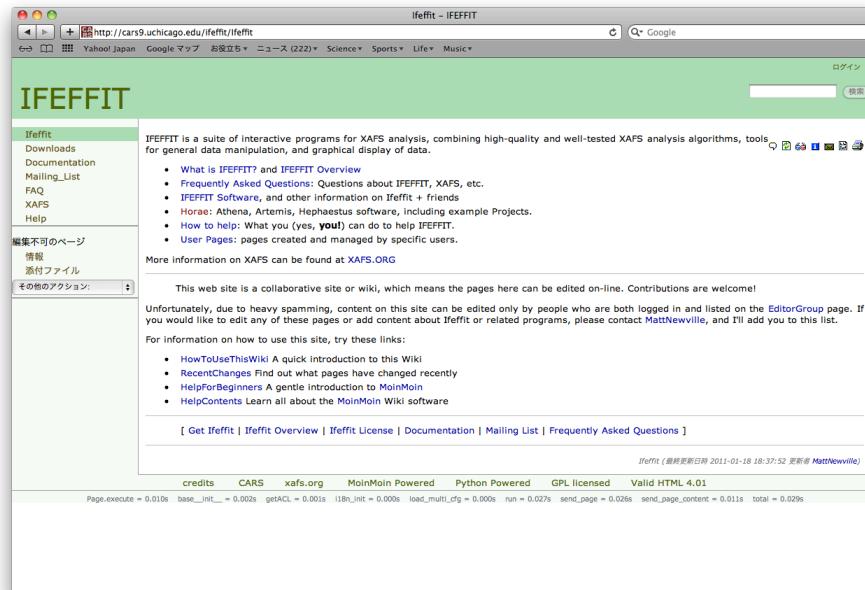


# Software for XAFS analyses

## Athena, Artemis (Ifeffit)

by a group at U. Chicago

<http://cars9.uchicago.edu/ifeffit/ifeffit>



## REX2000

by RIGAKU corp.

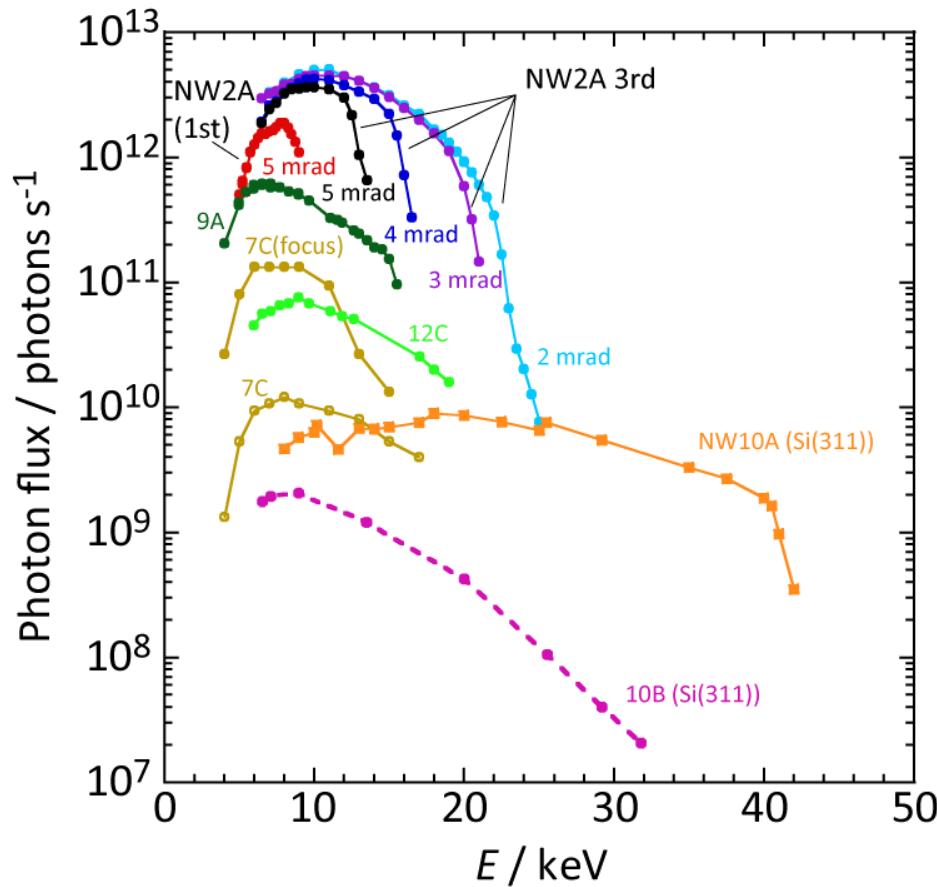
<http://www.rigaku.co.jp/products/p/xdxa0020/>



*Of course, there are many other softwares, and you can use what you'd like to.*

# Experiments of XAFS

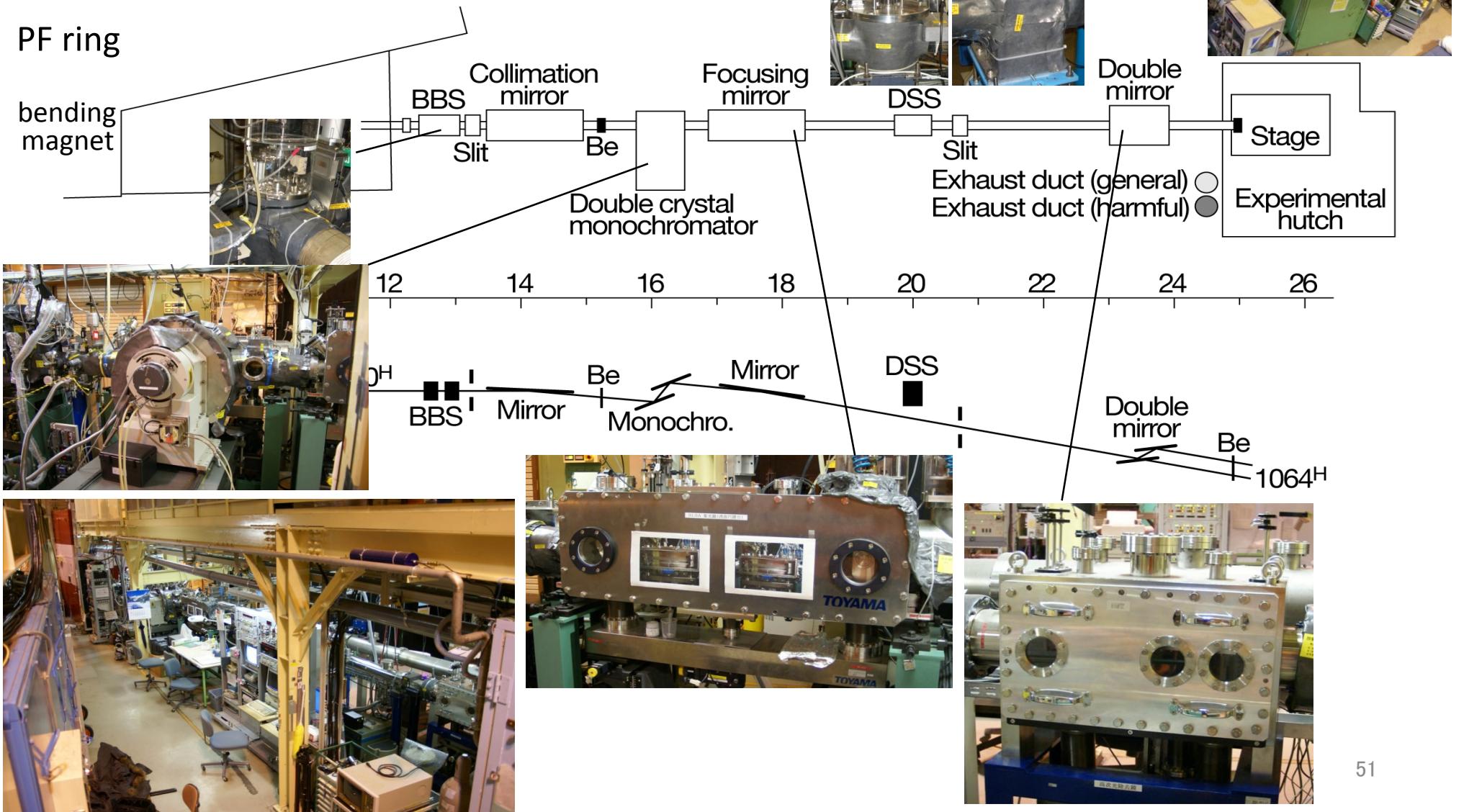
# Stations of XAFS experiments at PF



*K* edges: from P ( $\sim 2.1$  keV) to Ce ( $\sim 40$  keV)

*L* edges: from Mo ( $\sim 2.5$  keV) to U ( $\sim 21$  keV)

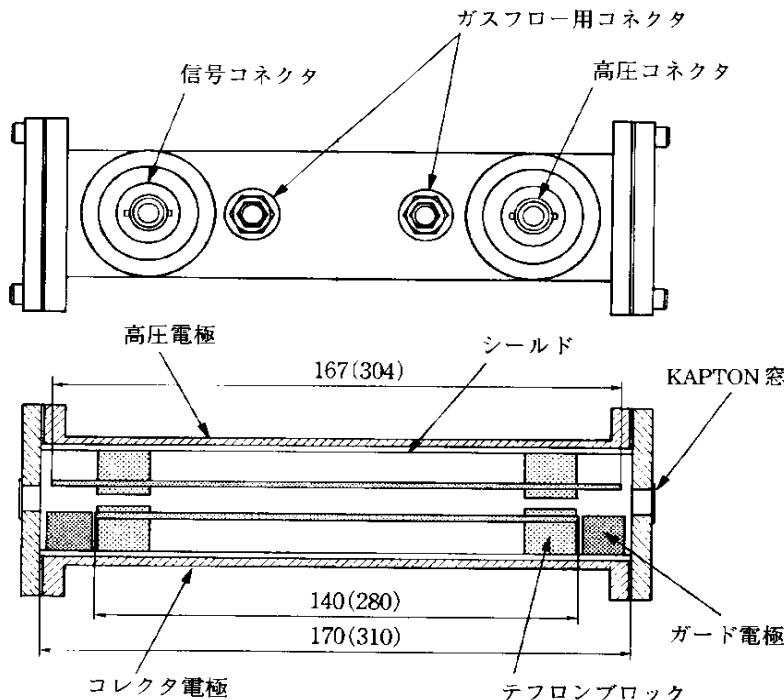
# Schematic of BL-9A



# Ionization chamber for x-ray detection



We measure the current produced by ionization of gas by incoming x-ray.



Current  $i$  ; measuring with  $N_2$  flowing ion chamber  
to detect x-ray of 8 keV;

$$i \approx 8.5 \times 10^{-8} \text{ A}$$

$$i = \alpha E e N / W$$

$\alpha$  : 検出効率(0.2)

$E$  : 光子エネルギー(8000 eV)

$e$  : 電荷素量( $1.6 \times 10^{-19}$  C)

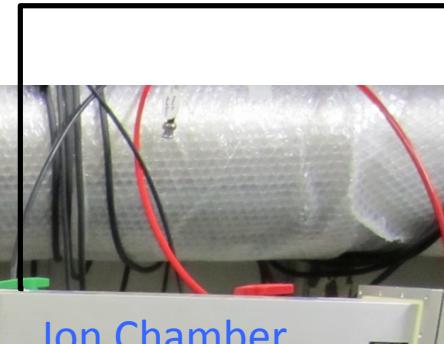
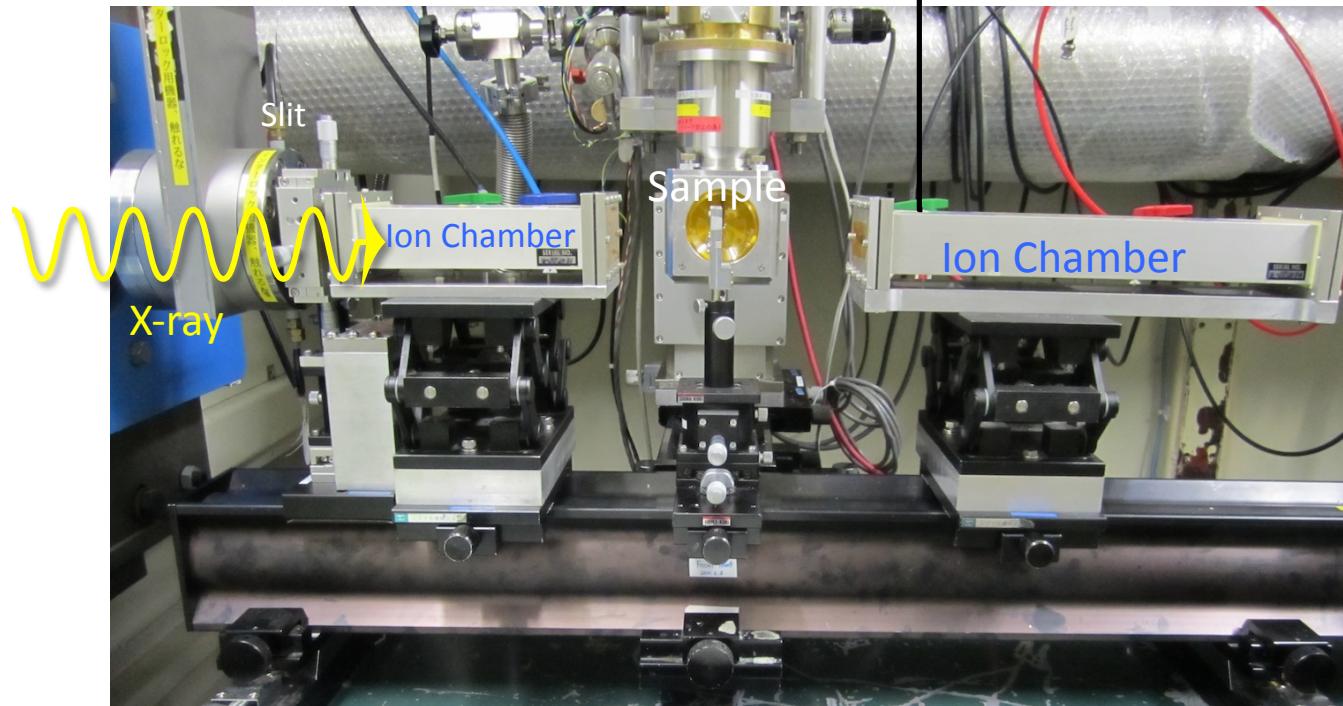
$N$  : 入射光子数( $10^{10}$  photons/s)

$W$  : 窒素ガスのイオン化エネルギー(30 eV)

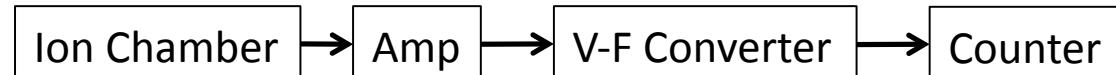
# Setup of transmission mode XAFS

Absorption

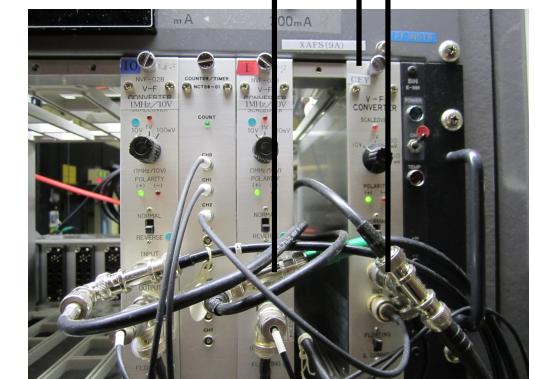
$$\mu t(\lambda) = \ln\left(\frac{I_0(\lambda)}{I(\lambda)}\right)$$



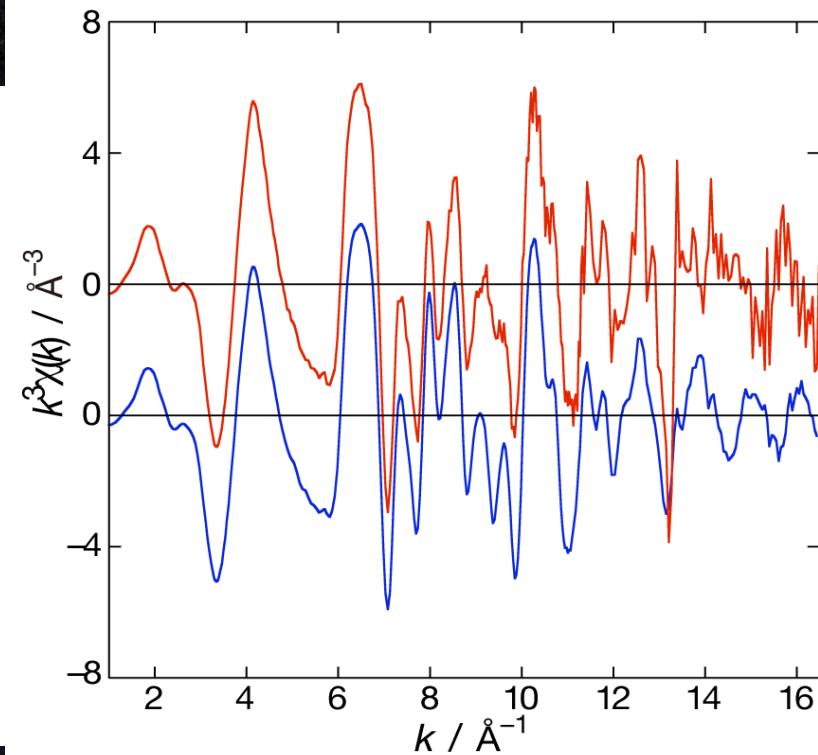
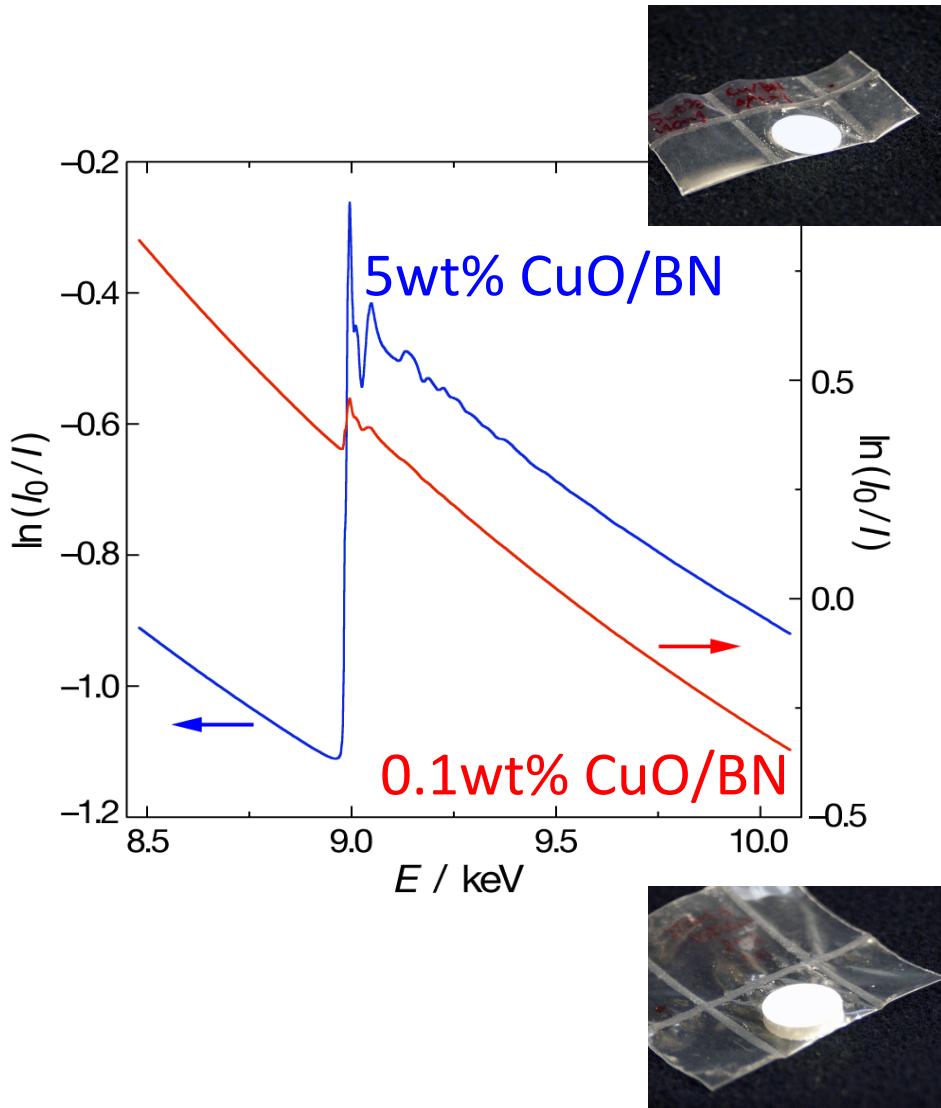
Current prop. to x-ray intensity



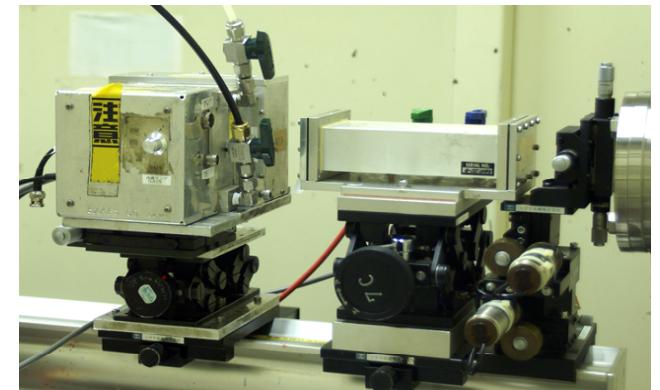
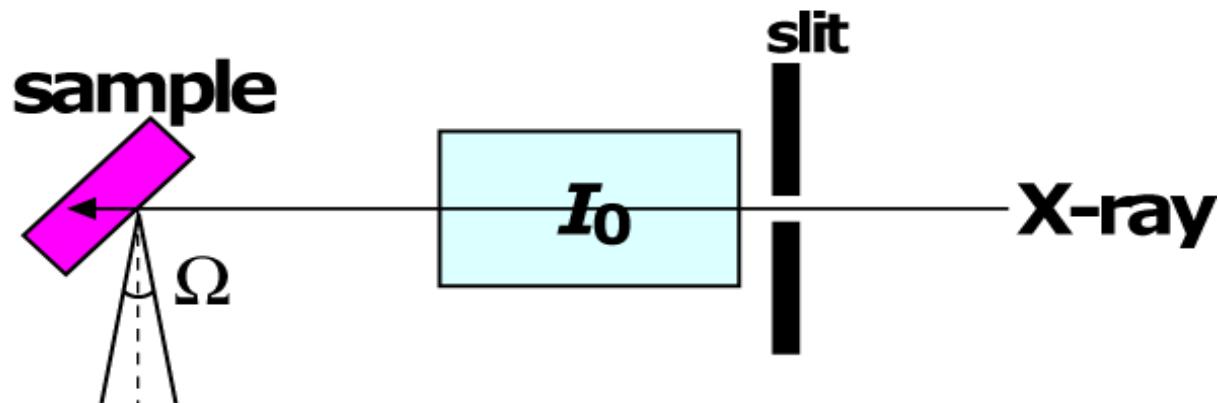
Cur. => Volt.    Volt. => Frequency



# Transmission mode XAFS spectra



# Fluorescence mode XAFS



$$I_f = I_0 \varepsilon \frac{\Omega}{4\pi} \frac{\mu_x(E)}{\mu_t(E) + \mu_t(E_f)} \left[ 1 - \exp\{-(\mu_t(E) + \mu_t(E_f))d\} \right]$$

$$\{(\mu_t(E) + \mu_t(E_f))d\} \ll 1$$

$$I_f = I_0 \varepsilon \frac{\Omega}{4\pi} \mu_x(E) d$$

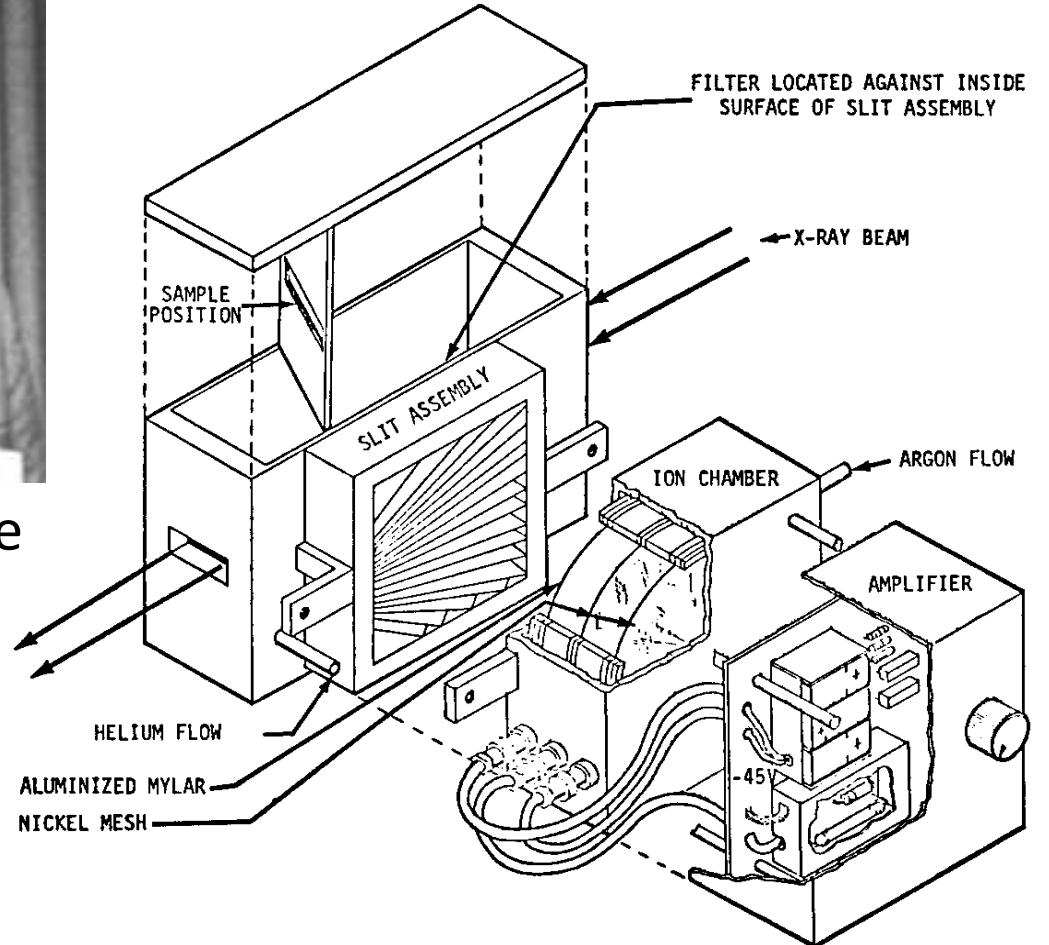
$$\therefore \frac{I_f}{I_0} \propto \mu_x(E)$$

thick but dilute  
(ex. 0.01 M aq.)  
concentrated but thin  
(ex. 1000 Å film)

# Ion chamber for Fluo. XAFS: Lytle Detector



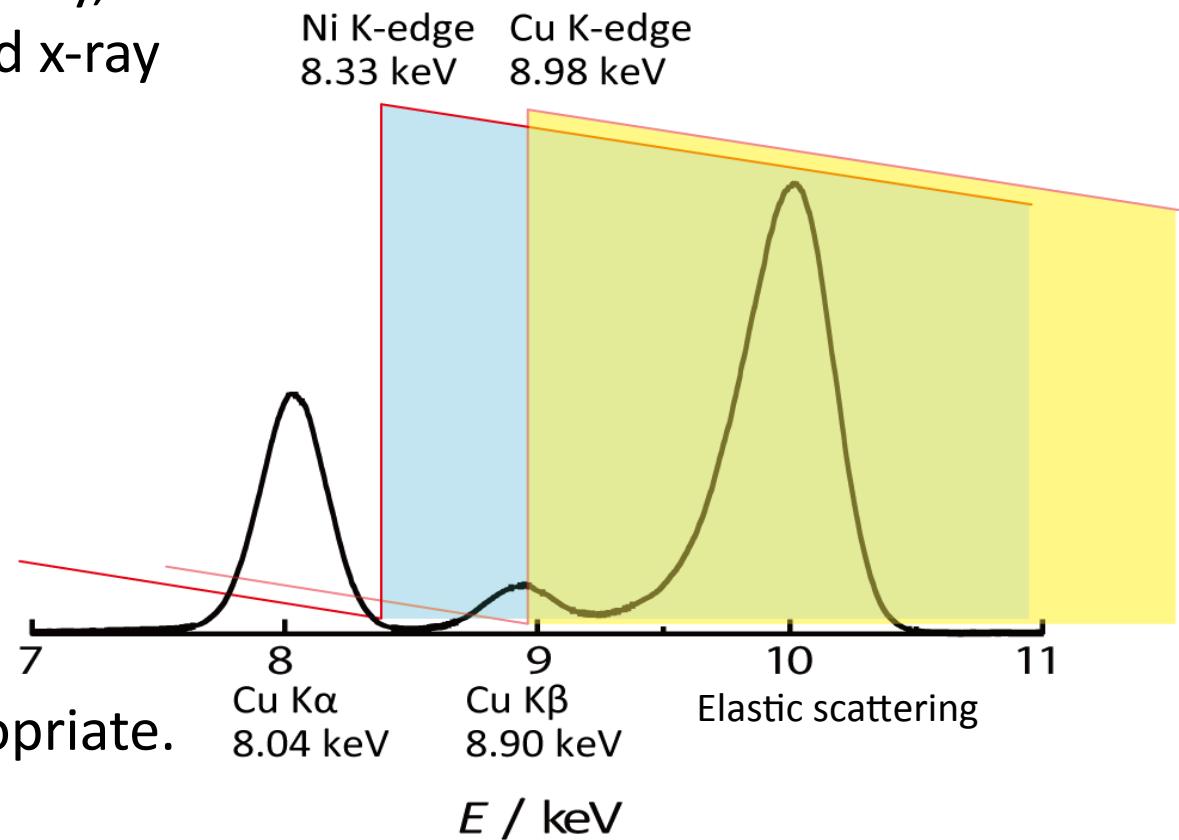
Dr. Farrel W. Lytle



*Not expensive, large solid angle, home made possible*

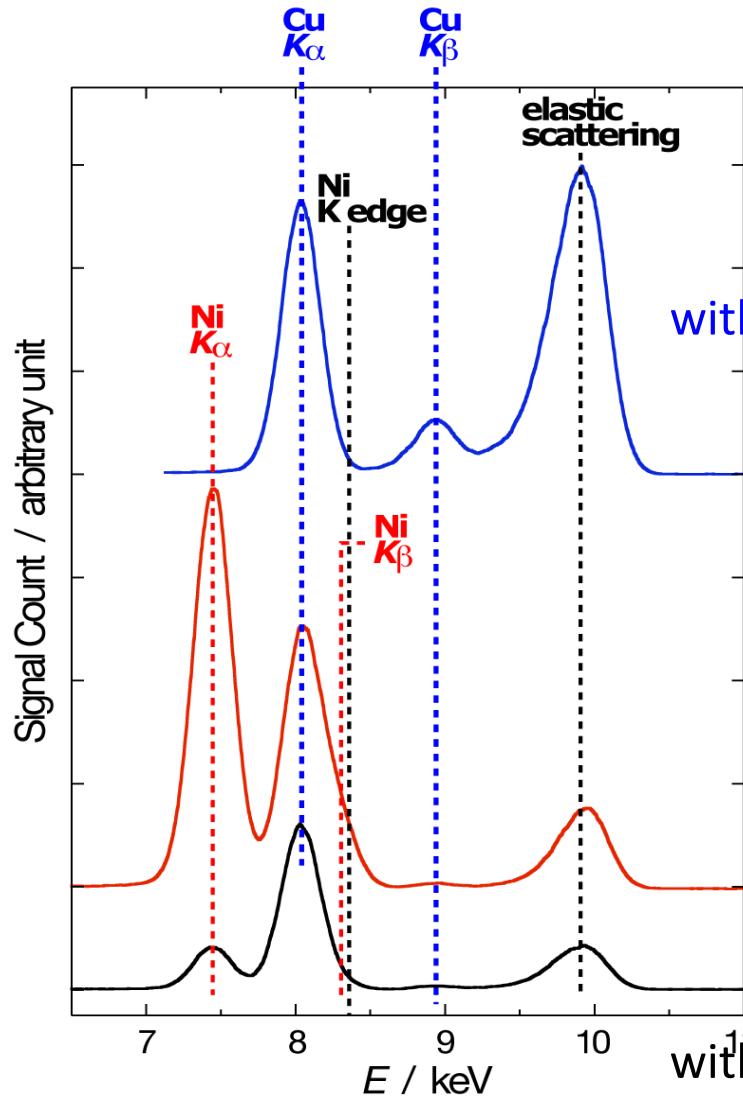
# Function of the filter

Transparent for Fluorescent x-ray,  
absorbing elastically scattered x-ray

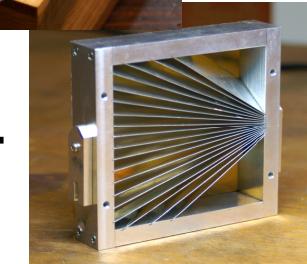
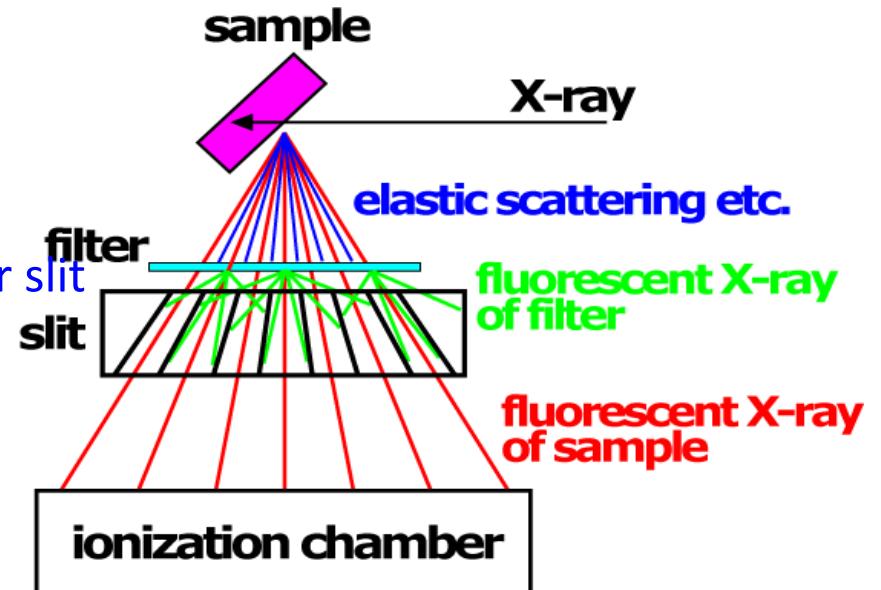


A "Z-1" filter is mostly appropriate.

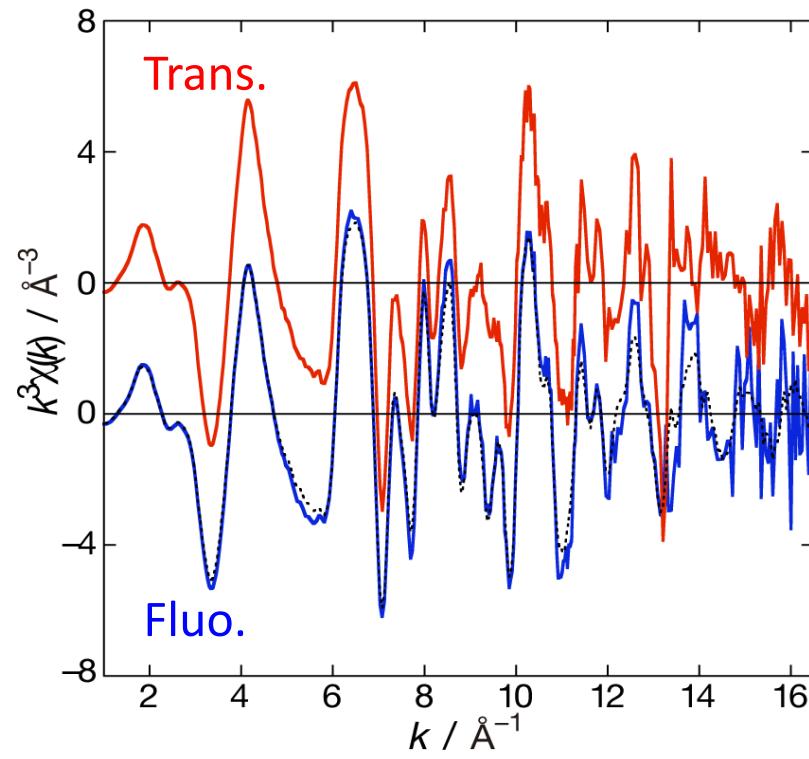
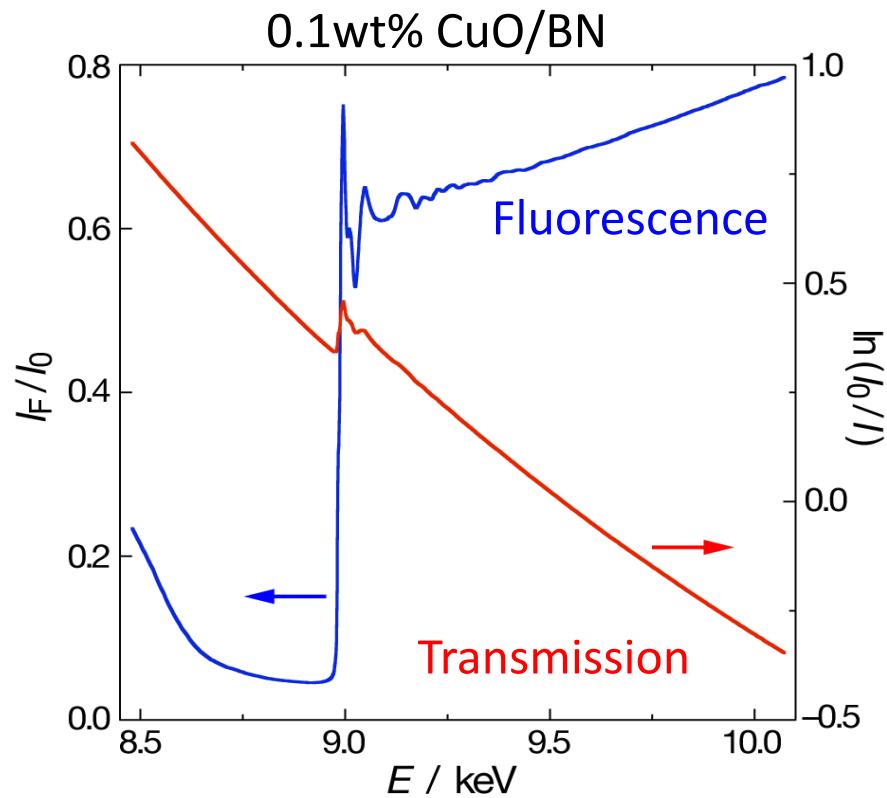
# Function of Filter & Soller slit of Lytle detector



Sample: 2 mM CuSO<sub>4</sub> aq.

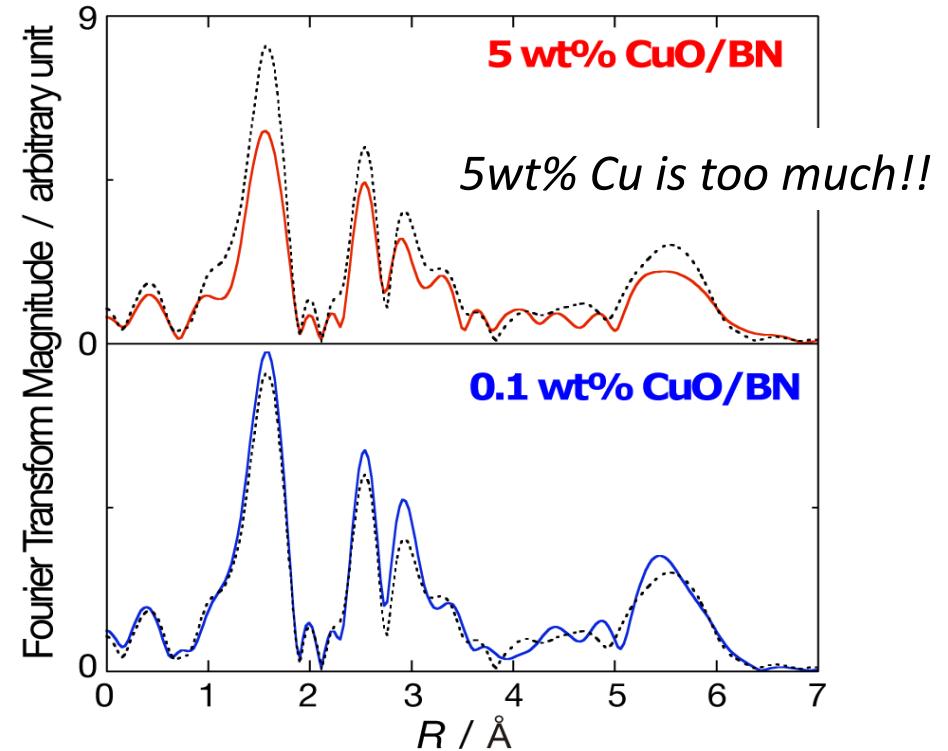
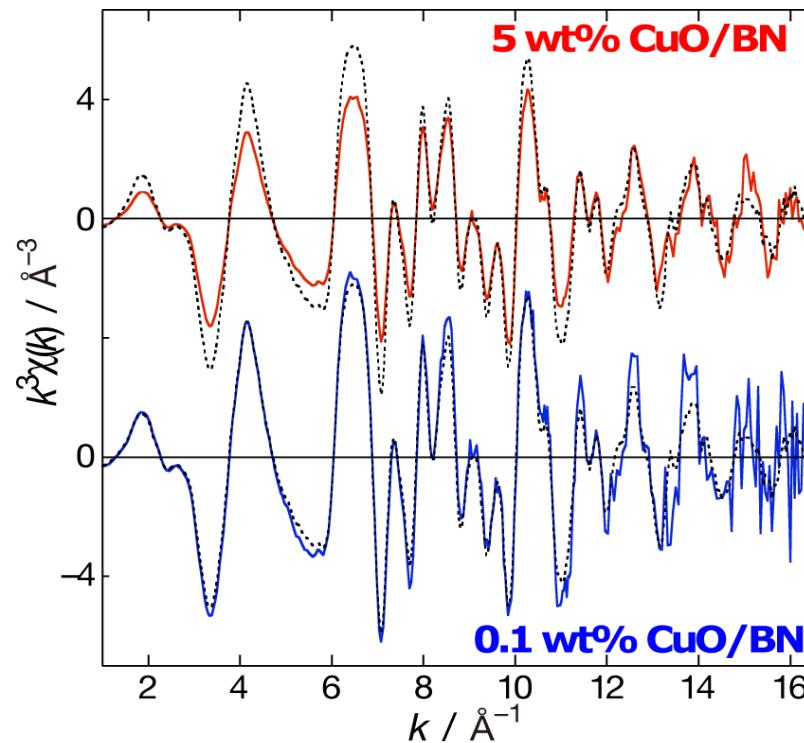


# Trans. mode & Fluo. mode



# Suitable sample for Fluo. mode XAFS

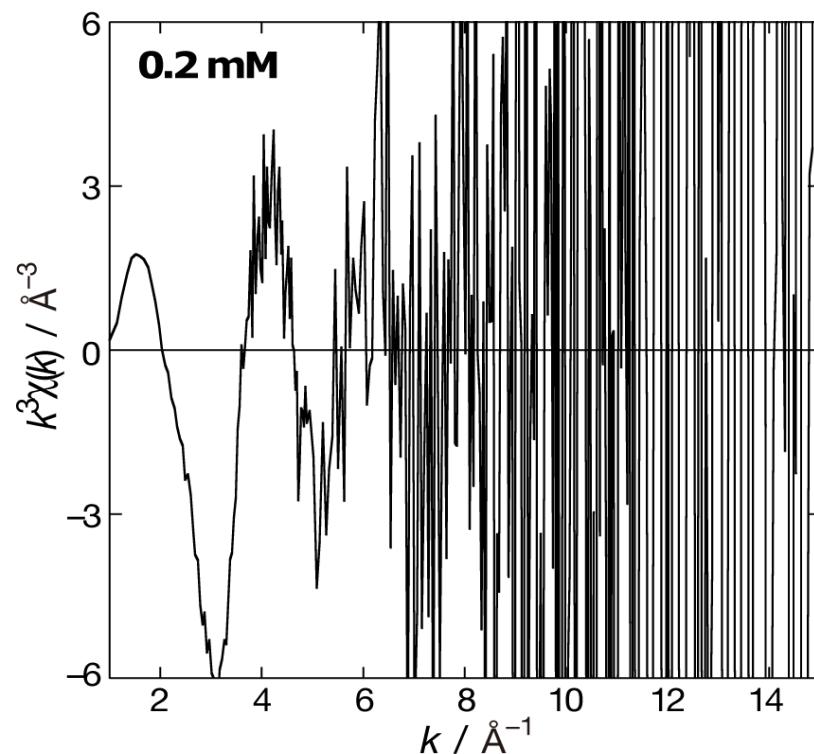
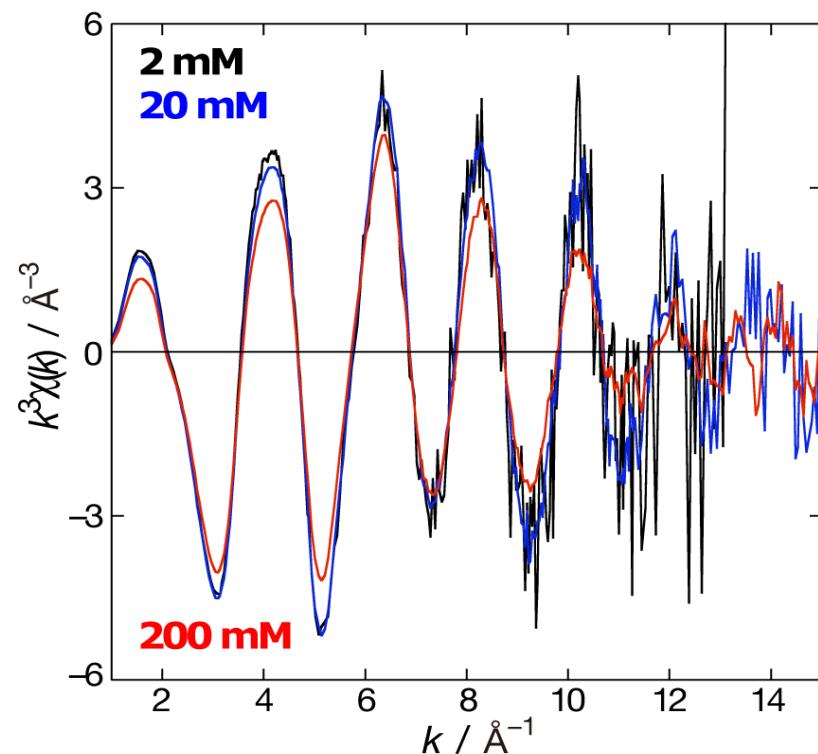
dotted line: trans mode XAFS for 5wt% sample



*Samples for Fluo. mode XAFS must be...*

- thick but **dilute**: ex. 0.01 M (10 mM) aq.
- concentrated but **thin**: ex. 1000 Å thin film

# Suitable sample condition for Fluo. mode XAFS



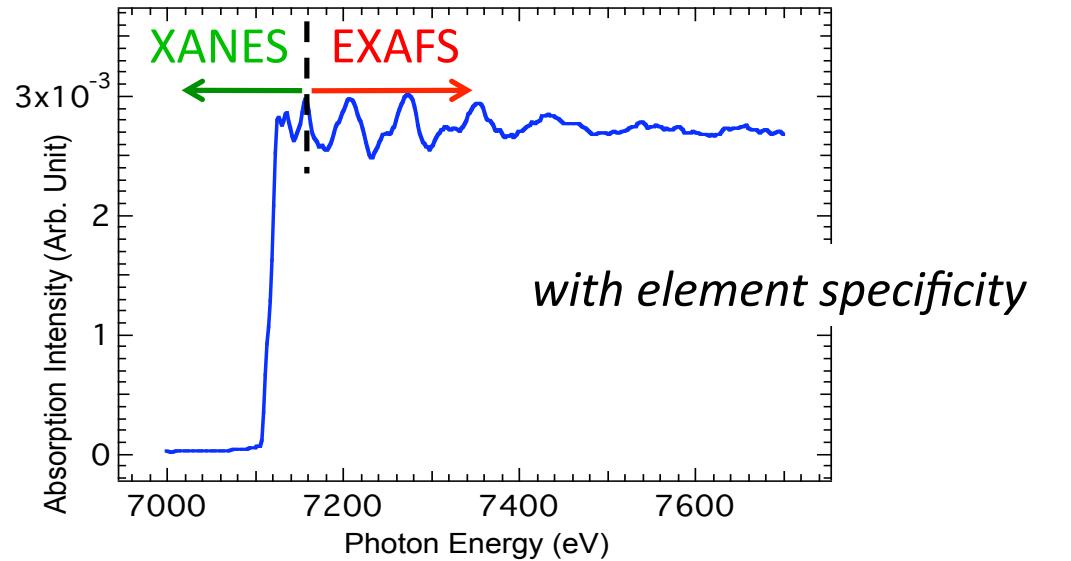
for  $\text{CuSO}_4$  solution

density	0.2 mM	2 mM	20 mM	200 mM
weight percent	0.0013 wt%	0.013 wt%	0.13 wt%	1.3 wt%
atomic percent	0.00036 at%	0.0036 at%	0.036 at%	0.36 at%

# Take-home message

XAFS : XANES + EXAFS

- XANES gives us...
  - Valence state
  - Symmetry
- EXAFS gives us...
  - Bond length
    - A local structure is given.
    - Crystallinity, or long range order is not required.
  - Coordination number (CN)
    - Simply, the number of atoms around the atom.
    - CN enables us to estimate sizes of nano clusters.



*The ruler is de Broglie wave of electron!!*